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Ferroelectricity Newsletter

A quarterly update on what's happening in the field of ferroelectricity

Volume 3, Number 1

Winter 1995

INTERNATIONAL FLAVOR OF FERROELECTRICS -- AN INDISPUTABLE FACT

The emphasis of this issue of the *Ferroelectricity Newsletter* -- the first one in our third year of publication -- is on conference reports from around the world: from Australia, Thailand, Japan, Germany, and Russia.

Pierre-Yves Lesaichere of NEC Corporation writes about the **55th Autumn Meeting of the Japan Society of Applied Physics**, held from 19 to 22 September 1994 in Nagoya City, Japan.

Information about the **2nd Pacific Rim Conference on Ferroelectric Applications** is provided by **Maria Huffman** of Symetrix, Colorado Springs, and **Jim Scott** of RMIT Melbourne gives an overview of the **Third Regional Seminar on Microelectronics and Information Technology**.

Rainer Waser of Aachen University of Technology and chairman of Electroceramics IV and **Steven Butow** of San José State University, California, report on the **4th International Conference on Electronic Ceramics and Applications**, which took place from 5 to 7 September 1994 in Aachen, Germany. The extensive list of presentations at this conference fills more than a third of the pages in this issue.

We end our trip around the world of ferroelectrics meetings with a description of the main events at the **6th International Seminar on Ferroelastic Physics** in Voronezh, Russia, from 12 to 15 September 1994, which **Stanislav Gridnev** of Voronezh State Technical University put together for us.

The article on the developments and markets of **Piezoelectric Actuators/Ultrasonic Motors** by **Kenji Uchino** of The Pennsylvania State University, promised for this issue, will come out in Spring 1995.

The international flavor that pervades every aspect of ferroelectrics is a strong sign pointing into the future: progress will be best achieved through cooperation between countries and continents.

A prerequisite for cooperation is information exchange through communication. Therefore we again thank our contributors and those who assisted them behind the scenes for their important work in the field of ferroelectrics.

Rudolf Panholzer
Editor-in-Chief

IN THIS ISSUE

From the Editor	1
Papers	
Electroceramics IV	2
Japan Soc. Appl. Physics	18
TARSMIT '94	25
Conference Reports	
Electroceramics IV	2
Japan Soc. Appl. Physics	16
ISFP-6, Voronezh	22
2nd Pacific Rim Conf.	24
TARSMIT '94	25
Upcoming Meetings	
CSC'2; 8th EMF	26
EMIF1; LEES2	27
Calendar of Events	28

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**ELECTROCERAMICS IV
PAPERS****DIELECTRIC AND MICRO-
WAVE MATERIALS**

Chemistry and Properties of
Perovskite-Type Rare Earth Titan-
ates for Microwave Applications
D. Kolar

**Structure-Property Relations in
Microwave Dielectrics**

*N. Setter, E. Colla, I. Reaney, R.
Zumuhlen, A.K. Tagantsev*

**Infrared and Near-Millimeter
Dielectric Spectroscopy of Some
Commercial Microwave Ceramics**

*J. Petzelt, G.A. Komandin, V.V.
Votsekhovskii, V. Koukal*

**Measurement of Complex Permit-
tivity in the Microwave Range**

R. Kurze, A. Schönecker

**Permittivity of Fine Grained
BaTiO₃**

J.C. Niepce

**Effects of A-Site Ion Substitution on
Pараelectric Properties of Perovskite
Compounds**

*H. Ikawa, M. Touma, T.
Shirakami, O. Fukunaga*

**The Insulator-Semiconductor
Transition in Perovskite Oxides**

*C.C. Dong, M.V. Raymond, D.M.
Smyth*

**Ionic Relaxation in Thin Anodic
Valve Metal Oxide Films**

A.W. Hassel, M.M. Lohrengel

**Dielectric Ceramics in the System
SnO₂-ZrO₂-TiO₂**

*E. Andronescu, A. Folea, G.
Bakila*

CONFERENCE REPORTS***ELECTROCERAMICS IV: 4th International Conference on
Electronic Ceramics and Applications***

*We are fortunate to have two contributions reporting on
ELECTROCERAMICS IV, the first written by Prof. Dr.-Ing. Rainer
Waser, chairman of the conference, and the second by Steven J.
Butow, who also provided the list of papers delivered at the confer-
ence (see pages 2 - 15 of this issue).*

History

Initialized by the Belgian Ceramic Society, Electroceramics I and II were held as international conferences on electronic ceramics in Brussels in 1984 and 1988 respectively under the presidency of Prof. Duvigneaud.

The third conference of this series was organized in Maubeuge, France, in 1992. Based on the big success of this series and the growing number of participants, the Planning Committee decided in May 1993 to reduce the conference cycle to two years. In addition, it was decided to further strengthen the international character by incorporating more colleagues from the United States and the Far East into the Advisory Board. This is of special importance due to the fact that Electroceramics is the only conference which comprehensively covers all areas of electronic ceramics. Hence the conference is immensely important for a mutual exchange of knowledge between different areas. The Planning Committee recommended the Institut für Werkstoffe der Elektrotechnik (IWE) at the Aachen University of Technology (RWTH) to organize the conference for 1994.

Organizing Committee and Advisory Board

The Organizing Committee comprises the members of the permanent Planning Committee as well as persons from universities and industrial companies who represent the field of functional ceramics in Germany, the host country. In addition, many presidents of national ceramic societies within Europe are engaged in the Organizing Committee due to the fact that Electroceramics IV is now held--for the first time--under the auspices of the European Ceramic Society. For the Advisory Board we were able to engage many internationally renowned specialists of the different areas within electronic ceramics.

Scientific Program

The scientific program consisted of eight sessions of different lengths which ran partially in parallel. For every session we had two to four invited lectures, depending on the session size, and a limited number of contributed lectures. In addition, we organized a poster session with approximately 220 posters. The following invited speakers have been engaged for the sessions:

1. *Dielectrics and Microwave Materials*
J.C. Niepce, University of Dijon (France)
D. Kolar, University of Ljubljana (Slovenia)
2. *Ferroelectrics, Piezoelectrics, Relaxors*
K. Uchino, Penn State University (USA)

CONFERENCE REPORTS

ELECTROCERAMICS IV -- continued from page 2

- G. Arlt, RWTH Aachen (Germany)
 D. Damjanovic, Ecole Polytechnique Federale de Lausanne (Switzerland)
 A. Kingon, North Carolina State University (USA)
 P. Osbourne, GEC (Great Britain)
3. *Grain Boundary Controlled Materials*
 P. Abelard, ENSCI, Limoges (France)
 E. Olsson (Sweden)
 T. Norby, University of Oslo (Norway)
4. *Electronic and Ionic Conductors*
 A. Feltz, Siemens Matsushita Components (Austria)
 B.C.H. Steele, Imperial College of Science (Great Britain)
 T. Norby, University of Oslo (Norway)
5. *Superconductors*
 B. Raveau, ISMRa Laboratoire CRISMAT (France)
 J. Maier, MPI für Festkörperforschung, Stuttgart (Germany)
 P. Komarek KfK Karlsruhe (Germany)
6. *Substrates and Integrated Functions*
 P.H.M. Keizer, Philips Components (The Netherlands)
 A. Okamoto, TDK Coporation (Japan)
 R. Tummala, IBM Corporation (USA)
 U. Ender, Murata Inc. (Germany/Japan)
7. *Magnetics*
 J. Pankert, Philips Forschungslaboratorium Aachen (Germany)
 P. Görnert, IPHT Jena (Germany)
8. *Processing and Mechanical Properties*
 B. de With, Technical University of Eindhoven (The Netherlands)
 M. Klee, Philips Forschungslaboratorium Aachen (Germany)

Results of the Conference

As the major task of the conference, the organizers considered further stimulation of the interaction between basic material sciences and the future development of electroceramic components, such as sensors, actuators, LCR components, and others. The related basic sciences comprise solid state physics and chemistry, electrochemistry, surface physics, microanalysis, crystallography, theoretical electrical engineering, and material technology. A new focal point at Electroceramics IV was an individual session on integrated functions, a first in the history of the conference. This topic deals with the joint sintering of different electronic ceramics (e.g., high permittivity ceramics, microwave ceramics, resistive ceramics, PTC and varistor ceramics) to a multifunctional integrated monolith. Technologically, this means a large step toward further miniaturization since printed circuit boards and passive substrates become--at least to a large extent--replaced by mechanically self-supporting ceramic functions. This new trend obviously poses a variety of new questions within the basic science disciplines, such as high temperature thermodynamics and kinetics.

This trend toward further integration of materials became obvious along

-- continued on page 4

ELECTROCERAMICS IV PAPERS continued

Chemical Reactions and Dielectric Properties in the BaTiO₃-LaAlO₃-La₄Ti₃O₁₂ System

S. Skapin, D. Kolar, D. Suvorov

High Permittivity Microwave Ceramics - the Influence of Ba_{4.5}Gd₉Ti₁₆O₅₄ Addition on the Temperature Stability of Dielectric Properties

M. Valant, D. Suvorov, D. Kolar

Dielectric Ceramics Based on (1-x)BaTiO₃xBaMg_{0.33}M_{0.67}O₃

E. Andronescu, A. Folea, A. Rahaianu

Sintering at Low Temperature of BZn_{1/3}Ta_{2/3}O₃ Ceramics: Influence of the Process on the Dielectric Properties

V. Tolmer, G. Desgardin

Anomalous Low Temperature Dielectric Behavior of Bismuth Pyrochlores

D.P. Cann, C.A. Randall, T.R. Shrout

Microwave Properties of Ferroelectrics and Antiferroelectrics with Admixed Gd₂O₃

S. Sugihara, M. Okajima, N. Hoshino, H. Ohuchi

An Effective Method for the Prediction of Lifetime of the Ceramics Capacitors

J. Pogorzelska

Perovskite Ferroelectric Material and X-Ray Diffraction Diagram

C.M. Valot, J.F. Berar, M. Bessiere, N. Floquel, M. Mesnier, J.C. Niepce, P. Perriat

-- continued on page 4

**ELECTROCERAMICS IV
PAPERS** continued

NaNbO₃ Doped BaTiO₃ Based
Dielectric for Capacitors Applica-
tion

*N. Bernaben, S. Achour, A.
Harabi, M.T. Beniehrache, S. Sahli*

Pure Barium Titanate Ceramics:
Crystalline Structure and Dielectric
Properties as Function of Grain Size

*N. Bernaben, A. Leriche, B.
Thierry, J.C. Niepce, R. Waser*

Dielectric Properties and Sintering
Conditions in BaTiO₃ Ceramics

C. Proust, E. Husson

Ferroelectric Green Ceramics:
Influence of the External "Stresses"
on the Ferroelectric Domain Struc-
ture

*P. Sarrazin, J. Lerreitre, J.C.
Niepce, B. Thierry*

BaTiO₃ Ferroelectric Ceramics
Sintered at Low Temperature with
the Aid of a Mixture of CaF₂ and
LiF

L. Benziada, J. Ravez

Dielectric Materials with Flat Curve
and High Dielectric Constant:
Mechanism of Reaction between the
Tetragonal Tungsten Bronzoid KSN
and the Perovskite PMN

B. Boulrou, G. Desgardin

Effect of Grain Orientation on the
Curie Temperature of KSr₂Nb₅O₁₅
Solid Solutions

T. Kimura, S. Saiubol, K. Nagata

Characterization of the Perovskite-
Layer Structure, SrBi₈Ti₇O₂₇

*I. M. Reaney, M. Roulin, H.S.
Shulman, D. Damjanovic*

CONFERENCE REPORTS**ELECTROCERAMICS IV** -- continued from page 3

three independent routes:

1. The integration of aspects of structural ceramics (mechanical properties, fracture toughness, reliability) is increasingly important for the development of electronic ceramic components. This applies especially to microengineering, which will lead to a closer cooperation between electrical and mechanical engineers.
2. The integration of different electronic ceramics (e.g., dielectric, magnetic, ion conducting) in monolithic multifunctional components (e.g., combination of different sensors and actuators) gains further emphasis. Integrated ceramic substrates will increasingly be used as substrates for silicon chips in surface mount technologies.
3. The integration of electroceramic thin films on silicon chips opens a field of growing activities. The modern silicon chips (microprocessors, logic chips) offer considerable "intelligence." While the function of the "brain" in a microsystem is further elaborated every year, the silicon chip can offer sensor and actuator functions only to a very limited extent. These functions are realized by various electronic ceramics integrated as thin films.

Besides these R&D related aspects, we recognized an increasing need for communication between scientists and engineers working in the different fields of electronic ceramics, especially due to accelerated activities during the last years and the high innovation rate we currently encounter. According to the response of the participants, this need obviously has been nicely matched by the Conference.

Sponsorship

The Conference has been held under the auspices of the European Ceramic Society. The organizers gratefully acknowledge financial support obtained by the Deutsche Forschungsgemeinschaft (DFG) and the Ministry of Science and Technology of Northrhine-Westphalia.

-- Rainer Waser

Steven Butow's Report on Electroceramics IV

The program of the Fourth International Conference on Electronic Ceramics and Materials was organized by Dr. Rainer Waser of the Aachen University of Technology and Philips Research Laboratory.

Electroceramics IV was successful in promoting the exchange of ideas and experiences of more than 400 participants. This year's meeting hosted scientists and engineers from more than thirty countries, including Latvia, Slovenia, China, and Korea. Of course, Japan, the United States, and European communities were well represented.

Electroceramics IV was planned with two specific goals in mind. First, to bridge the gap between basic science and industrial applications; and second, to integrate different ceramic functions in order to broaden the scope of our respective disciplines. With respect to the latter, an interesting combination of electroceramic and structural ceramics talks highlighted the impor-

CONFERENCE REPORTS

ELECTROCERAMICS IV -- continued from page 4

tance of mechanical stresses, fracture, and thermal effects on materials. The momentum necessary for an integration of ceramic functions has been well established by microelectronics industry. In the future, the scope of electroceramics will include electrooptics, "highly intelligent" or "wise" silicon chips, and advanced piezoelectric devices.

A renaissance of fundamental fields is underway. Areas such as crystal chemistry, thermodynamics, phase relations, and kinetics were revisited throughout the conference. Likewise, there is renewed interest in defect chemistry for its relevance to superconductors and grain boundary phenomena. Microwave science is also emerging as a possible analytical tool capable of providing a new view of the microceramic world.

Despite the advances realized in recent years, problems of mechanical reliability, processing flaws, chemical contamination and production costs remain. The need for "better, faster, cheaper . . ." continues to provide the impetus for more study. Fortunately, there are many talented scientists and engineers who are dedicated to continuing the research and development necessary to meet the demands of the present, while forging new technologies for the future.

Electroceramics will most certainly continue to play a vital role in communications, semiconductors, and microdevices which impact every aspect of our lives.

Conference proceedings are published as a two-volume set (ISBN 3-86073-287-0 by Verlag der Augustinus Buchhandlung). The next International Conference on Electronic Ceramics and Applications (Electroceramics V) will be held in Aveira, Portugal, in 1996. The conference chairman will be J.L. Baptista, Universidade de Aveiro.

-- Steven Butow

PROFESSOR L. ERIC CROSS

UFFC-S DISTINGUISHED LECTURER FOR 1994-1995

Professor Cross, well-known in ferroelectrics circles as teacher and researcher and to the readers of the *Ferroelectricity Newsletter* as author of the history of ferroelectricity, has been nominated by the Administrative Committee of the Ultrasonics, Ferroelectrics, and Frequency Control Society as the UFFC-S Distinguished Lecturer for 1994-1995. In this capacity he is speaking before UFFC-S chapters, graduate and undergraduate student university seminars, IEEE groups, and other appropriate scientific and engineering associations. His topic is:

**Ferroelectric Materials for
Electromechanical Transducer Applications.**

ELECTROCERAMICS IV PAPERS continued.

Synthesis and Dielectric Properties of Complex Perovskites with Different Oxygen Vacancies in the System SrO-Ta₂O₅

*J. Takahashi, K. Kodaira, T. Ota,
M. Takahashi*

Effect of Bi₂O₃ and Sintering Temperature on Pyrochlore Structure in the Bi₂O₃-ZnO-Nb₂O₅ System

H. Wang, B. Huang, X. Wang, X. Yao

Structural Study of Cubic Pyrochlore in the Bi₂O₃-ZnO-Nb₂O₅ System

H. Wang, X. Wang, I. Zhang, X. Yao

Formation Mechanism of Bismuth-Zinc-Niobium Oxide Pyrochlores

X. Cai, X. Yao

The Preparation and Structures of Bismuth-Based Oxide and Oxyfluoride Pyrochlores

X. Cai, X. Yao

Anomalous Resistivity Behavior of Praseodymium Doped Barium Lithium Niobate

K.S. Rao, K.K. Rao, C. Srinivasudu, A.S.V. Subrahmanyam

Experimental Research of Ceramic-Polymer Boundary

L.A. Pasechnik, A.I. Carpov, V.F. Zavorotny

Frequency and Power Characterization of Multilayer Ceramic Hi-Cap Capacitors by Infrared Thermography

D. Darrouzes

-- continued on page 6

ELECTROCERAMICS IV PAPERS continued

Fast Transient Measurements on Electroceramic Thin Films

G.W. Dietz, M. Schumacher, R. Waser

Loss Measurement of Microwave Ceramics by the Ghost-Mode Technique

J. Baur, Ch. Hoffmann, R. Waser

Electrode Influence on the Charge Transport Properties of SrTiO₃ Thin Films

W. Antpöhler, G.W. Dietz, M. Klee, R. Waser

Relationship between Processing and Dielectric Loss of MgTiO₃ Based Ceramic Resonators

V.M. Ferreira, J.L. Baptista

**FERROELECTRICS,
PIEZOELECTRICS,
RELAXORS**

New Piezoelectric Devices for Smart Actuator/Sensor Systems

K. Uchino

Strong Dielectric Dispersion in Ferroelectric Ceramics at Microwaves

G. Arit

In Situ Studies of Phase Transitions in Ferroelectric Perovskites

I.M. Reaney

La-Modified Pb(Mg_{1/3}Nb_{2/3})O₃-Based Relaxor Ferroelectric Ceramics

T. Takenaka, H. Takagi

Pyro-Ferro- and Dielectric Properties of PLT Thin Films

Y. Liu, W. Liu, L. Zhang, X. Yao

Ferroelectric Ceramics for Uncooled

Infrared Detectors

P.C. Osbond, R.W. Whetmore

Sputtered Ferroelectric Films for Pyroelectric Detectors

R. Bruchhaus, H. Huber, D. Pilzer, W. Wersing

Structure and Chemical Compositions of PLZT Thin Films and Their Ferroelectric Properties

J. Hector, N. Floquet, D. Aymes, P. Gaucher

Phase Transitions and Radiation Damage in Lead Containing Perovskites for Applications in Electrooptics and Electronics

A. Sternberg, L. Shabanov, E. Birks, H.W. Weber, F.M. Sauerzopf, H. Schwabl

High Temperature Piezoelectric Ceramics and Extrinsic Contributions to their Properties

D. Damjanovic

Grain Growth in Multilayer PZT

J. Wen, H. Hellebrand, D. Cramer, K. Lubitz, G. Tomandl

Piezoelectric Coatings on Fibers

G.R. Fox, M. Kosec, P.A. Danai, N. Selter

Electrostrictive Properties of Based PbMg_{1/3}Nb_{2/3}O₃(PMN) Bulk Ceramics

E. Lattard, M. Lejeune, M. Oudjedi, C. Leblanc, P. Marquigny, C. Pecquet, P. Abelard

Structure-Property Relations for Ferroelectric Materials: Thin Films vs. Bulk

A. Kingon, C.E. Miller

Dielectric Design in Ferroelectric

Thin Films

L.E. Cross

Defect Chemistry Model of the Time Dependent Electrical Response of Ferroelectric Memories

C.J. Brennan

Bistable Conduction in Metal-Ferroelectric Schottky Contacts

P.W.M. Blom, R.M. Wolf, J.F.M. Cillessen, M.P.C.M. Krijn

Film Thickness Dependence of Dielectric Properties on BaTiO₃ Films Prepared by Sol-Gel Method

T. Hayashi, N. Oji, H. Maiwa

Microstructure and Dielectric Properties of Sol-Gel Barium Titanate Thin Films on Nickel Alloy Electrodes

O. Sugiyama, T. Ogawa, S. Sailoh, A. Kondo, H. Masuola

F_{RL}-F_{RH} Transition in Nb Doped Pb(Zr_{0.965}Ti_{0.035})O₃ Ceramics

B. Noheda, T. Iglesias, G. Lilante, J.A. Gonzalo, H.T. Chen, Y.L. Wang, J. deFrutos, G. Shirano

Rapid Thermal Processing of Lead Zirconate Titanate Thin Films from High Molarity Sols

S. Meridein, A. Berger, S. Wahl, W. Grond, D. Spom

Preparation and Characterization of PZT Thin Films Derived from Metalloorganic Precursors by a Two-Step Heat Treatment

S.B. Xiong, X.Q. Wu, L.Y. Zhang, X. Yao

Preparation and Application of PZT Thick Films

L. Settner, H.-J. Gesemann

ELECTROCERAMICS IV PAPERS continued

Integration of PZT-Based
Microactuators on Silicon

O. Josi, P. Otschik, A. Schönecker

Obtention of La Modified Lead
Titanate Films by an Alternative
Chemical Method

J. Baltazar-Rodrigues, J.A. Eiras

Crystalline and Structural Analysis
of Modified Lead Titanate Ferro-
electric Thin Films by the GIXRD
Method

*J. Mendiola, M.L. Calzada, R.
Sirena, P. Ramos*

Structure and Optical Properties of
Magnetron R.F. Sputtered Lead
Titanate Thin Films

*D. Remiens, B. Jaber, E.
Dogheche, P.Y. Jouan, B. Thierry*

Preparation and Ferroelectric
Properties of (Pb,Lu)TiO₃ Thin
Films by Multiple Cathode Sputter-
ing

*K. Okazaki, H. Maiwa, N.
Ichinose*

Laser Ablation Deposition of
Ferroelectric Lead Zirconate Titan-
ate and High T_c Superconducting
Y-Ba-Cu-O Layers

*J. Levoska, S. Leppävuori, T.
Murtoniemi, J. Lappalainen*

Deposition of Ferroelectric Layers
by Thermal Spraying

*W. Häßler, R. Thielsch, M.
Menzel, K. Fischer*

Preparation and Characterization of
PLT Thin Films by Hot-Wall LP-
MOCVD

S.-S. Lee, H.-G. Kim

Preparation of Thin Films of Titan-

ates and Zirconates by an Electro-
chemical-Hydrothermal Method

F. Schlenkrich, M. Eber

Preparation and Properties of
BaTiO₃ Films by Electrophonetic
Deposition

*T. Walari, K. Shigernaisu, T.
Torikai, O. Matsuda*

Direct Determination of Relaxation
Distribution Function in Dielectrics
Upon Experimental Data

M.A. Leshchenko, V.P. Bovtun

Statistical Properties of Random
Spin-1/2 XY Chains

*O. Derzhko, T. Krokhmal'ski, T.
Verkholyak*

Measurement and Simulation of the
Signal Behavior of Piezoelectric
Actuators

*H. Janocha, D. Jendritza, J.
Feiler, P. Stephan*

Comparison of Different Methods
for the Displacement-Field Charac-
terization of Piezoelectric Materials

*M.G. Gee, M. Stewart, N.J.
McCormick*

Aging after Polarization Reversal in
Acceptor Doped Ferroelectrics

U. Robels, A. Mellage, G. Arlt

Degradation of Multilayer Ceramic
Actuator

K. Nagata, S. Kinoshita

Temperature Stabilized Ceramic
Piezoelectric Elements

K. Nagata, E. Harashima

Elaboration of LiNbO₃-Based
Piezoelectric Ceramics

*L. Nibou, S.G. Brodie, C.E.
Millar, J.P. Mercurio*

Ferroelectric Ceramics in the
Na_{0.5}Bi_{0.5}TiO₃-K_{0.5}Bi_{0.5}TiO₃,
Na_{0.5}Bi_{0.5}TiO₃-PbTiO₃ and
K_{0.5}Bi_{0.5}TiO₃-PbTiO₃ Systems

*O. Elkechai, P. Marchet, J.P.
Mercurio*

The Influence of Processing and
Microstructure on Piezoelectric and
Mechanical Properties of Fine
Grained PZT Ceramics

M. Demartin, C. Carry, N. Setter

The Effect of Interfacial Reaction
on the Physical Properties of PZT

L.G. Yao, R.J. Brook

X-Ray Diffraction Study of the
Structure of Lead Zirconate and
Modified Lead Titanate Ceramics

*V. Vasilescu, M. Anghel, M.
Spätanu*

Effect of WO₃ Additions on the
Microstructure and Electrical
Properties of PZT Ceramics

*M.R. Soares, F. Coimbra, A.M.R. Senos, P.Q. Mantas, J.L.
Baptista*

Processing Sol-Gel PZT Thin Films
for Microactuators

*K.G. Brooks, I.M. Reaney, T.
Maeder, N. Semer*

Non-linear Piezoelectric Metrology:
Coefficients under Impact

J.A. Close, R. Stevens

Beading Strains in Piezoelectric
Ceramics in the Electric Field

*G.M. Akbaeva, V.Z. Borodin, A.V.
Prikhodkov*

High Field De-Aging and Fatigue
Characteristics of Hard PZT
Ceramics

D.A. Hall, C.E. Millar

ELECTROCERAMICS IV PAPERS continued

Relaxor Characteristics of PLZT 9/65/35 Related to Raw Material Morphology

D. Garcia, E. Nassar-Moreira, J. Ballazar-Rodrigues, J.A. Eiras

The Investigation of Impurities Anomalous Influence on PLZT Ceramic Properties

I.P. Bykov, M.D. Glinchuk, V.V. Lagula, Y.L. Maksirnenko, L. Jasirabik, V. Dimza, M. Boudysh, L. Soukup

Electrooptic Properties of Sol-Gel Derived PT/SiO₂ and PZT/SiO₂ Glass Composites

Q. Zhao, K. Yao, L. Zhang, X. Yao

Optical Spectra of PLZT Ferroelectric Ceramics

Z. Bryknar, I. Bykov, V. Dimza, L. Jashabik, A. Savinov, L. Soukup, V. Trepakov

Total-Reflection Type Optical Modulator Utilizing Surface Acoustic Wave

T. Utsunomiya

Characterization of Magnesium Diffused Lithium Niobate Substrates by XRD

W. Que, L. Zhang, X. Yao

A Logic Gate on Surface Acousto-optic Devices

C.Y. Shen

(Pb_{1-x}Ba_x)Sc_{1/2}Nb_{1/2}O₃ Electrooptical Ceramics

M. Darnbekaine, A. Sternberg, K. Bormaris

The Use of Additives in the Low Temperature Sintering of KTN Ceramics

A. Pigram, J. Ravez, J.P. Bonnet

Pb(In_{1/2}Nb_{1/2})O₃ Ceramic: Preparation and Nanostructural Studies

J. Ravez, F. Weil, C. Elissalde

Dielectric Properties of Field-Induced Transition in Pure or Doped Ceramics Pb(Mg_{1/3}Nb_{2/3})O₃

M. Malki, M. Chabin, E. Husson, C. Proust, A. Morell

Glassy State and Field-Induced Ferroelectric State in PbMg_{1/3}Nb_{2/3}O₃

P. Calvi, P. Camagni, E. Giulotto, L. Rollandi

Improving the Properties of PMN Ceramics by Selective Doping

K. Reichert, F. Schlenkrich, L. Seffner

Newly Developed Piezoceramic Material With High d₃₃/d₃₁ Ratio

S.A. Gridnev, N.G. Pavlova, S.P. Rogova

Ferroelectric Properties of the Mixed Aurivillius Phase

Bi_yTi₄NbO₂₁
R. Maalal, M. Manier, J.P. Mercurio, B. Frit

Processing and Sintering of CaBi₄Ti₄O₁₅ Powders for High-Temperature Piezoelectric Materials

C. Moure, J.F. Fernandez, M. Villegas, P. Duran

Microstructural and Electrical Properties of Doped Bi₄Ti₃O₁₂ Ceramic Materials for High Temperature Piezoelectrics

C. Moure, J.F. Fernandez, M. Villegas, P. Duran

Ferroelectric and Resistivity Properties of Modified Ba₆Ti₂Nb₈O₃₀

Ceramics

K. Sambesiva Rao, A.S.V. Subrahmanyam, C. Srinivasudu

Optimal Sizes of Crystallites for Ferroelectric Piezoceramic Materials for Various Purposes

A.Y. Dartsiger, L.A. Reznitchenko, O.N. Razumovskaya, S.i. Dudkina, S.V. Gavilyalchenko, N.V. Dergunova

Novel Anisotropic Piezoceramic Materials: Their Properties and Application

L.D. Grineva, V.A. Servuli, R.A. Molchanova

Modified Solid Solutions on the Basis of LiNbO₃

V.A. Chernyshkov, L.A. Reznitchenko, L.D. Grineva, L.A. Shilkina

Piezoceramic Materials on the Basis of Binary Systems of Solid Solutions Assisted by Li Metaniobate for High Temperature Applications

L.A. Reznitchenko, N.V. Dergunova, V.A. Chernyshkov

Structural Criterion of Search and Modeling of Piezoelectric Materials on the Basis of High-TcPTZ

N.V. Dergunova, L.A. Reznitchenko, A. Ya. Dantsiger, O.N. Razumovskaya

Active Dielectrics-Ferroelectric-Piezoceramic Solid Solutions and Their Applications in Filter Techniques

S.V. Gandyatchenko, A.Ya. Dantsiger, A. Reznitchenko

High-Stability Piezoceramic Materials for Frequency-Selective Devices

ELECTROCERAMICS IV PAPERS continued

S.V. Gandyatchenko, A.Ya. Dantsiger, A. Reznitchenko

Conditions of Existence of Ferroelectric Properties in Oxides Having the Tetragonal-Tungsten-Bronze-Type Structure

R.U. Devlikanova

SHF Dielectric Properties of the Piezoelectric, Electrostrictive and Capacitor's Materials with Some Structural Disorder

Yu. I. Yakimenko, V.P. Bovtun, M.A. Leshchenko

Some Physical Aspects of Large Piezoelectric Anisotropy Problems in Ferroelectric Ceramics

A.V. Turik, V. Yu. Topolov

Domain Switching and Anisotropy of Piezoelectric Moduli in PbTiO₃-Type Ceramics

A.V. Turik, V. Yu. Topolov, A.I. Chemobabov

On the Relation Between Single-Crystal and Ceramic Physical Properties in PbTiO₃-Based Ferroelectrics

A.V. Turik, V. Yu. Topolov

Modeling of the Dielectric Behavior of Ferroelectric Relaxors

Z.G. Lu, G. Calvarin

Ceramics of Pb(Fe_{2/3}W_{1/3})O₃ Prepared by the Columbite Precursor Method

L. Zhou, P.M. Vilarinho, J.L. Baptista

Ferroelectric Solid Solutions with Low Coercive Force for Memory Devices

G.M. Akbaeva, A.Ya. Dantsiger, O.N. Razumovskaya

GRAIN BOUNDARY CONTROLLED MATERIALS

Present Understanding of the Grain Boundary Electrical Characteristics of Semiconducting BaTiO₃ and SrTiO₃ Ceramics

P. Abelard

Fabrication of Multilayer Semiconducting BaTiO₃ Ceramics with PTCR Characteristics

S. Tashiro, A. Kanda, H. Igarashi

Localized Measurements of the Transient and Steady State Thermal Response of BaTiO₃ Thermistors to Applied Voltage

D.S. Smith, I. Charrisou, M. Zamora, P. Abelard

Investigation on the Microscopical Origin of the PTC Effect in Nb-Doped Barium Titanate

C. Gillot, J.P. Michenaud, I. Baukens, P.H. Duvigneaud

Control of the Electronic Properties by Control of Grain Boundary Structures of ZnO Varistors

E. Olsson

Comparison by Impedance Spectroscopy of Varistors Prepared by Traditional Route or by Soft Chemistry

I. Guy, R. Legros, A. Rousset, J.M. Lattargue, A. Loubiere, A. Bui

Preparation and Characterization of Pulse Resistant ZnO-Pr Low Voltage Varistor

D. Mund, G. Tomandl

Formation of Energy Barrier by Contact of ZnO

S. Fujitsu, S. Hidata, K.-I. Kawamura, Y. Awakura, F. Noritake

PTCR and NTCR Phenomena in NaNbO₃ Doped BaTiO₃ Based Dielectric Materials

N. Benhamia, S. Achour, A. Harabi, M.T. Benlahrache

Low-Temperature Cathodoluminescent Studies on BaTiO₃ Ceramics

U. Marx, T. Hübner, M. Mitle, J. Schreiber

Role of Arklitives in the High-Field ZnO-Based Varistors

H.T. Nguyen, A. Bui, A. Loubiere

Influence of the Molibdemium in the Microstructure and Electrical Characteristics of Varistor

R.H.G.A. Kimivarni

The Effect of Heat Treatment in Electrical Inhomogeneity of Zinc Oxide Varistor Ceramics

A.I. Ivon, A.B. Glot

Nonlinear Properties in ZnO Film Based Varistors

N. Ichinose, K. Yamaji

Impedance Characterization of Grain Boundary Doped SrTiO₃

M. Vollmann, R. Waser

A Characterization Method of Varistors Degradation Based on Complex Plane Analysis (CPA)

J-M. Laffargue, A. Loubière, A. Bui

Aging Study of ZnO-Based Varistors under Electrical Combined Stresses for DC Systems Arresters Application

C. Talhi, A. Bui, A. Loubière, S. Leuimi

Effect of Hydrogen Plasma on the

ELECTROCERAMICS IV PAPERS continued

Cathodoluminescence of ZnO
Ceramics

S. Achour, M.T. Benlahrache, A. Harabi

Cathodoluminescence from Doped
ZnO Ceramics

S. Achour, M.T. Benlahrache, A. Harabi

Influence of the Electrical Heterogeneity on the Determination of Electronic Levels in the Forbidden Gap of SrTiO₃ Capacitor Material

F. Poignant, P. Abelard

Grain Boundaries in SrTiO₃ Internal Boundary Layer Capacitors Infiltrated with Bi₂O₃ or a Bi₂O₃-PbO Mixture

F. Poignant, G. Troliard, P. Abelard

Influence of Domain Structure on the Charge Transport in PTCR Ceramics

A.N. Pavlov, I.P. Raevsky

Linearization of PTC-Ceramics Resistance-Temperature Dependence under Constant Current Conditions

I.P. Raevsky, A.N. Pavlov, M.A. Malitskaya, Y.M. Popov

Grain Boundaries in Electronic Ceramics: Simulation of the Electrostatics and the Defect Chemistry

R. Hagenbeck, R. Waser

How to Circumvent the Grain Growth Anomaly in Donor Doped BaTiO₃ Thermistors

L. Schneider-Störmann, R. Waser

Grain-Boundary Decorated Titanate

Ceramics: Processing and Properties

L. Schneider-Störmann, M. Vollmann, R. Waser

ELECTRONIC AND IONIC CONDUCTORS

Ceramic Materials for SOFC and Electrochemical Reactor Technology

B.C.H. Steele

Trends in the Development and Application of Negative Temperature Coefficient Oxide Ceramics

A. Feltz

Electrical Transport in Highly Conducting Titanates

R. Moos, W. Meneskiou, A. Gnuxli, K.-H. Härdil

Electrical Conductivity and Defect Structure in the System Sr Ti_{1-x} Fe_xO_{3-y} (x=0.1-0.8)

S. Steinsvik, T. Norby, P. Kofstad

Theory of Oxygen Transport Through Mixed Conducting Perovskites

M.H.R. Lankhorst, H.J.M. Bournmeester, H. Verweij

Protonic and Native Ionic Conductivity in Oxides

T. Norby, Y. Lauring

Ionic and Electronic Conductors for Solid Oxide Fuel Cells

W. Schäfer, D. Stolten

Ceramic Components for Solid Oxide Fuel Cells (SOFC) With Metallic Interconnector

E. Ivers-Tiffée, W. Wersing, H. Greiner

Impedance Spectroscopy Analysis of the Electric Behavior of Ceramic Composites

M. Kleitz, E. Djurado, P.O. Robert, M.C. Steil, F. Thevenot

Electrical Conductivity of LaMnO₃-Based Perovskites

G. Stochniol, E. Syskakis, E. Wennelskirchen, A. Naoumidis, H. Nickel

Impedance Response of Yb-Doped SrCeO₃ in a Water Vapour Free Environment

M. Cappadonia, L.G.J. de Haart, Th. Matzke, U. Stimming

Vacuum-Tight Joints of Proton-Conducting SrCeO₃ and α-Al₂O₃ for Use in an Electrochemical Hydrogen Gas Sensor

K. Vercammen

Na-Beta-Alumina-a Mixed Ionic-Electronic Conductor

H. Näfe

Dynamic Characteristics of SaTiO₃ Thick Film as an Oxygen Sensor

S.-S. Cho, H.-G. Kim

Electrical Conductivity Change with Crystallization of Some Alkali Alumino Silicate Glasses

S.N. Salama, and Z S. El Mendouh

Gas and Humidity Sensitive Electrical Properties of La₂CuO₄-ZnO Hetero-Contacts

E. Traversa, A. Bearzotti, M. Miyayama, H. Yanagida

Ionic Conductivity Measurements of Natural Fluorite at Low Temperature

M.C. Amemra, H. Kimczyk, M. Filal, G. Petot-Ervas, C. Petot

ELECTROCERAMICS IV PAPERS continued

Effects of Structural Disorder on the Optical Properties of Cubic Stabilized Zirconia

M. Bassi, P. Camagni, G. Samoggia, S. Torre

Electrical Properties of Sb-Doped SrO_2 Powders, Ceramics and Single Crystals

G. Behr, J. Werner, P. Donkir, G. Couturier, D. Elefant

Lowering of the Cathode Overpotential of SOFC by Electrolyte Doping

P. Bohac, A. Orliukas, L.J. Gaucider

Electrical Conductivity of β -Alumina Based Electrolytes

M.M. Bucko, G.Rog

Electrical Properties of Thick Film Silicon-Doped α - Fe_2O_3 Humidity Sensor

C. Cantalini, H.T. Sun, M. Faccio, G. Ferni, M. Pelino

Composite (YSZ+LSM) Ceramic Filters With High Oxygen Electrochemical Permeability

A.D.S. Costa, J.A. Labrincha, F.M.B. Marques

Preparation and Properties of the High Temperature NTC Thermistor Ceramics

M. Diaconescu, M. Anghel, V. Ghita, M. Nicolae

Influence of the Microstructure on the Ionic Conductivity of Yttrium Doped Zirconia

M. Filal, C. Lacour, M.C. Amamura, G. Petot-Ervas, C. Petot

Electrical Conductivity of the Brownmillerite-Structured Oxides

$\text{Ba}_2\text{In}_{2-x}\text{M}_x\text{O}_5$

C.A.J. Fisher, R.J. Brook

Humidity Sensitive and Varistor to Dioxide Based Ceramics

A.B. Glot, A.M. Nedzhefzade, A.I. Ivon

Solid Solutions of Ternary Oxide Ceramics as Active Materials for Humidity Sensors

D.L. Hales, T. Hasherni, A.W. Brinkman

Activation Volume of Proton Transport in NH_4NbWO_6

R. Hinrichs, G. Tomandl, J.A.H. da Jomada

Oxide Ionic Conductivity of Lanthanum-Strontium Manganites Ceramics

V.V. Kharton, A.V. Nicolaev, E.N. Natimovich, J.S. Gayduk, A.A. Vecher

Electrochemical and Structural Properties of SnO_2 and $\text{Sb}:\text{SrO}_2$ Transparent Electrodes with Mixed Electronically Conductive and Ion-Storage Characteristics

U. Lawrencic Stanger, B. Orel, F. Svegl

Electrochemical Method of Determination of the Oxygen Diffusion Coefficient in Zirconia

M. Mokchah, M. Filal, C. Petot, G. Petot-Ervas

Thermopower of Highly Donor Doped $\text{Sr}_{1-x}\text{La}_x\text{TiO}_3$ -Ceramics

R. Moos, A. Grudi, K.-H. Händtl

Oxide Ionic Conductors in the System Bi_2O_3 - PbO - Y_2O_3

E.N. Naumovich, S.A. Skilkov, V.V. Kharton, A.A. Vecher

Oxide Ionic and Electronic Conductivity of $\text{SrCo}_{1-x}\text{M}_x\text{O}_3$ ($\text{M}=\text{Cr.}, \text{Cu}; x=0.05$)

A.V. Nikofaev, V.V. Kharton, E.N. Naumovich

Electronic Conduction of Nondense Silica Thin Films

U.C. Pernisz

Oxygen Tracer Diffusion in Doped Single Crystal Strontium Titanate

U. Kiessling, J. Claus, G. Borchardt, A. Waser

Electronic Conductivity and Lattice Defect Chemistry of In_2O_3 Solid Solutions

K. Sasatki, L.J. Gauckler

Influence of Grain Size and Grain Size Distribution on the Ionic Conductivity of Beta-Alumina Polycrystals

A.P. de Kroon, G.W. Schäfer, F. Aidinger

Synthesis and Properties of Spray-Dried $\text{SrCe}_{2-x}(\text{Yb}, \text{Y})_x\text{O}_{3-\alpha}$

E. Syskakis, L. Zimmermann, A. Förthmann, W. Jungen, T. Matzka, U. Stimming

Protonic Conduction of Barium Cerate

S. Tanishima, R.J. Brook

Electrical Properties of LaFeO_3 Sputtered Thin Films in NO_2 Atmosphere

E. Traversa, S. Matsushima, G. Okada, Y. Sadaoka, Y. Sakai, K. Watanabe

Atomic Defects and Ionic Conductivity in Y_2O_3 Doped CeO_2 and ZrO_2

ELECTROCERAMICS IV PAPERS continued

M. Weller, H. Schubert, D.D. Upachyaya

Mechanical Relaxation Measurements in the Protonic Conductors SrCeO₃ and SrZrO₃

L. Zimmermann, H.G. Bohn, W. Schilling, E. Syskakis

EPR Study of the Centrum Valence State in Nd_{2-x}Ce_xCuO₄

C.B. Azzoni, A. Paleani, F. Scardina, L. Bolis, G. Spinolo

Cathodic Polarization of La_{0.9}MnO_{3-δ} Screen-Printed Electrodes on Thin YSZ Electrolyte Layers

F.M. Figueiredo, J.A. Labrincha, J.R. Frade, F.M. Marques

Thermoelectric Properties of CdIn₂O₄ with Spiral Structure

Y. Ochi

Low Temperature Sol-Gel Syntheses of the Cubic Zirconium Oxide for Ceramic Solid Electrolyte Production

M.V. Taodikov, O.G. Ellert, O.V. Buckhienko, D.I. Kochubey

Electrical Properties of Bioactive Ceramics in a Broad Frequency and Temperature Range

H. Rall, P. Lunkenheimer, J. Alkemper, H. Fuess, R. Böhmer, A. Loidl

Kinetics of Charge Carriers in Nd₂CuO₄ and Nd₂Cu_{1-x}Li_xO₄₋₅ (0 < x < 0.25)

V.I. Makarov, V.Z. Kleiner, N.S. Tereshina, O.N. Razumovskaya
Volume Expansion, Tetragonal Distortion and Metal-to-Dielectric Transition Caused by Oxygen

Vacancies in LaCuO₃₋₆ and BaPb_{1-x}Bi_xO₃ Ceramics
S.A. Prosandeyev

Epitaxial Growth and Characterization of La Doped SrTiO₃ Thin Films

K.-O. Grosse-Holz, J.F.M. Cillessen, P.W.M. Blom, R. Waser

SUPERCONDUCTORS

The Mercury Based Cuprates; A Large Family of Metastable Superconductors

B. Raveau, M. Hervieu, G. van Tandelco, C. Michel, A. Maignan

Defect Chemistry in High Temperature Superconductors

J. Maier, M. Quilitz

Modeling of Thermodynamics and Phase Equilibria in Subsystems of the Bi-Sr-Ca-Cu-O System

B. Hallstedt, D. Risold, L.J. Gauckler

EBSF and SIMS Studies of Oxygen Traces Diffusion in the High Temperature Superconductor La_{2-x}Sr_xCuO_{4-δ}

J. Claus, G. Borchardt, S. Weber, S. Scherrer

The Oxygen Content of the High-Temperature Superconducting Compound Bi_{2+x}Sr_{3-y}Ca_yCu₂O_{8+d} with Respect to Varying Ca and Bi Contents

P. Majewski, H.L. Su, F. Aklinger

Possible Application of HTSC Ceramics in Power Engineering

P. Komarek

Enhancement in Critical Current Density of Ultra-Fine MgO Added Bi-2212/Ag Composite Tape Under Magnetic Field

H.-D. Kim, J.-W. Ko, S.-Y. Lee, K.-H. Ha, J.-H. Ahn, H.-S. Chung, K. Togano

Processing of YBaCuO by a Sol-Gel Precursor: Sintering and Weak Links Behavior

F.J. Gotor, P. Odier, N. Pellerin, A.R. Ferl

Melt Processing of YBa₂Cu₃O₇

G.J. Schmitz

Phase Diagrams as the Guide for Microstructure Control of Y-Ba-Cu-O Ceramics

G. Krabbes, P. Schätzle, U. Wiesner, W. Bieger, G. Stöver

Phase Equilibria in the System Bi₂O₃/PbO-SrO-CaO-CuO with Special Regard to the (Bi,Pb)₂Sr₂Ca₂Cu₃O_{10+d} Phase

S. Kaesche, P. Majewski, F. Aldinger

Thin Films of YBa₂Cu₃O_{7-x} for Microwave Applications

J. Musolf, E. Waffenschmidt, X. He, F. Arndt, K. Heime

Preparation and Characterization of YBa₂(Cu_{1-x}Zn_x)₃O_{7-δ} Thin Films

M. Ye, M. Mehbod, R. Deltour, Y.F. Guo, C. De Beck, P.H. Duvigneaud, G. Moorgal, F. Cambier

Phase Diagrams of the Systems La(Nd)₂Cu_{1-x}Li_xO_{4-δ} and La(Nd)₂CuLi_xO_{4+δ} in a Subsolidus Region

O.N. Razumovskaya, L.M. Rudkovskaya, I.A. Shilkina, V.I. Makarov

Electrochemical Deposition of Superconducting Bi-Sr-Ca-Cu-O

ELECTROCERAMICS IV PAPERS continued

and Ti-Bi-Sr-Ca-Cu-O Films on Silver Substrate

S. Chatterjee, S. Banerjee, B.K. Chaudhuri

Controlled Precipitation of Pinning Centers During Melt Growth of Freeze Dried Precursors

D. Dienickx, O. van der Biest, W. Boon, K. Rosseel, Y. Bruynseraede

Influence of the Oxygen Partial Pressure During Cooling Procedure, and Mechanical Stresses on the Superconducting Properties of Ag-Bi₂Sr₂CaCu₂O_x Screen-Printed Tapes

B.A. Glowacki

Sol-Gel Chemistry of Y-Ba-Cu-O System

M. Belle, S. Pejovnik

Synthesis of Single-Phase Bi₂Sr₃CaCu₂O_{8+δ} Superconductor by Spray-Drying Nitrate-EDTA Solution and Characterization

Y.-F. Guo, P.-H. Duvigneaud

Low Temperature and Low P_{O2} Preparation of Melt Quenched High-Temperature Superconducting Bi₂212 Bulk Ceramics

P. Majewski, S. Kaesche

Preparation, Characterization and Optimization of Y₁Ba₂Cu₃O_{7-x} and Bi₂Sr₂CaCu₂O_{8+δ} Thin Films

J. Auge, U. Rüdiger, B. Beschoten, H.G. Roskos, G. Güntherodt, H. Kurz

Bi-Sr-Ca-Cu Superconducting Ceramics Prepared from Amorphous Material

N. Nanba, M. Kolkubun, K. Nagata

Preparation and Densification of HTc (2223) Phase Superconductor

A. Tampieri, G. Celotti, G.N. Babini

Ferroelectric and Superconducting Properties of YBa₂Cu₃O_{7-δ} - BaTiO₃ Composites

S.A. Gridnev, S.A. Fadeev, S.P. Rogova

Determination of Temperature Dependence of Oxygen in YBa₂Cu₃O_x by Structure Refinements Based on Powder X-Ray Diffraction Analysis

K. Ikeda, T. Honjuchi, H. Shima

Low-Field Dependence of the Intergranular J_c Measured Using AC Susceptibility

A. Buekenhoudt, J. Cornelis

Polarized Light Microstructure Analysis of DYBa₂Cu₃O_{7-x} Melt Textured in Magnetic Field

P. Dilko, M. Ausloos, R. Cloots

YBa₂Cu₃O_{7-x} Superconductive Tapes and Wires: Suspension Spinning and Tape Casting Using a Phase Inversion Technique

H. Weylen, W. Adriansens, V. Bukenbergs, A. Buekenhoudt, R. Leysen, J. Cornelis

Densification of Y₂BaCuO₅ Substrates for Solid-Liquid Processing of YBa₂Cu₃O_{7-x} Superconductive Layers

L. Ryelandt, J. Lapin, F. Delannay
Grain Growth in YBa₂Cu₃O_{7-x} (123)-Y₂BaCuO₅ (211) Sintered Powder Composites

I. Sangankova, P. Dilko

Relaxation of Mechanically Milled YBa₂Cu₃O_{7-x} Studied by Differen-

tial Scanning Calorimetry

I. Sargankova, P. Dilko, S. Matas, J. Mihalik, M. Reissner, W. Steiner

INTEGRATED FUNCTIONS AND SUBSTRATES

Miniaturization and Integration of Passive Components by Multilayer Ceramic Technology

A. Okamoto

Ceramic Multilayer Modules: A New Concept for Integration of Passive Components

P.H.M. Keizer, W.R. DeWild

Integrated Passive Functions: Toward a New Generation of Chips

H. Salze

Composite "Moonie" Actuator and Its Reliability

A. Dogan, K. Uchino, R.E. Newnham

Multilayer Electronic Ceramics

D. Schmid, B. Hoffmann

Improvement of Multilayer Chip LC Filters Utilizing a New Ceramic Material for High Frequency, Low-Loss Functional Devices

U. Ender, B.E. Helms et al

SAW Properties of La, Sm Modified Lead Titanate Ceramics

C.E. Millar, L. Pedersen, L. Pardo, J. Ricole, C. Alemany, B. Jimenez, G. Feuillard, Y. Janin

Modern Substrate Concepts for the Microelectronic Industry

A. Roosen

Integrated Substrate

R.R. Tummela

ELECTROCERAMICS IV PAPERS continuedAl₂O₃-Al₂O₃ Laminnar Ceramics*J. Flavez, V. Andriamampiarina, J.L. Luliane, P. Letulier, J.M. Heintz*

Sintering and Properties of Aluminum Nitride Substrates

D. Liberi

Sintering of Ruthenium Oxide-Based Resistive Coatings

A. Niemann, G. Roche, P. Marchet, J.P. Mercurio

Diffusion of Titanium Into Aluminum Ceramics Using Active Solders

W.K. Wlosinski, W. Olesinska, A. Bien

Problems of Surface Conductivity in Electrical Resistance Measurements and Their Implication for the RIED Effect

*F. Scheuermann, W. Kesternich*Fabrication and Characterization of Erbium-Doped LiNbO₃ for Integrated Optics*M. Fleuster, L. Beckers, St. Bauer, W. Zander, Ch. Buchal, H. Holzbrecher, U. Breuer***MAGNETICS**

Recent Developments in Power Ferrites

J. Pankert

Effect of Additions on Electromagnetic Properties of High Frequency MaZn Ferrites

R. Lebourgeois, J.P. Garne, S. Pignard, P. Ganin, B. Ulonet

Dry Pressing of Thin-Walled Ferrite Potcores

M.J.M. de Graef, R.J.A. van der Drill, H.J. Glass

Low Temperature Sintering in Ni-Zn-Cu Ferrite

T. Nakamura, T. Tsukaoka

Microcrystalline and Nanocrystalline Hexaferrites Prepared by the Glass Crystallization Method

P. Gornert

Magnetostrictive and Demagnetizing Phenomena in Ferrites

P. Perriat, M. Guyot

3D-FEM Modelling of Ferrite Cores Power Losses and Corresponding Temperature Distribution

M. Esguerra, R. Lucke

Ferrimagnetic Thin Films Prepared by Pulsed Laser Deposition

M. Guyot, R. Krishnan, A. Lifei, M. Porte, M. Rabeut, P. Renaudin, P. Rougier, M. Tessier, V. Cagan

The Preparation of Fe-Ferrite and Its Magnetic Properties

M. Alavi, J. Amighian, E. Musavi

Preparation of Isotropic Ba-Hexaferrite Using Hematite By-Product of Local Steel Factory

J. Amighian, M. Mozaffari

The Preparation and Thermal Properties of Cobalt Ferroplana Single Crystal

S.J. Kim, T.O. Kim

Sol-Gel Derived Fine Hexaferrite Particles

*C. Sunig, K.A. Hempel, D. Bonnenberg, J. Roumen, H.-J. Klaar*Glass Crystallization of Nanocrystalline BaFe_{12-2x}Co_xTi_xO₁₉ Particles*R. Müller, W. Schüppel, P. Gornert*About New Magnetic CnLn₂Se₄*T. Koneshova, O.G., Ellert*

Microstructure and Electromagnetic Properties of Polycrystalline YIG Containing Dopants

J.-D. Lee, T.-O. Kim

Magnetic Susceptibility and Dielectric Studies on Iron-Titanium Oxygen System at Low Temperatures

R.P. Viswanath, A.T. Seshadri

Sol-Gel Processing of YIG Fibers and Films

*F. Essl, A. Thierauf, R. Jahn, D. Sporn, M. Baier, A. Forchel***PROCESSING AND MECHANICAL PROPERTIES**

Fracture of Dielectric Ceramics: A Brief Review

G. de With

Crack Growth in Ferroelectric Ceramics under Mechanical and Electrical Loading

G.A. Schneider, A. Rostek, B. Zickgral, F. Aldinger

Mechanical Reliability of Ferrite Cores: Thermo-Mechanical and Electrical Loading

L.J.M.G. Dortmans, M.J.M. de Graaf, G. deWith

Electric and Magnetic Field Contribution to the Microwave Sintering of Ceramics

A. Cherradi, G. Desgardin, J. Provost, B. Raveau

Spin-On Processing of Perovskite Thin Films for Innovative Microelectronic Devices

M. Klee

ELECTROCERAMICS IV PAPERS continued

Single Crystal Thin Films Via
Solution Precursor Processing
F.F. Lange

Chemical Homogeneity and Mor-
phology of Alkoxy-Derived PZT
Powders
M. Kosec, B. Malic

Processing and Properties of Wet-
Chemically Derived Modified PZT
Thin Films
*S. Seifert, S. Meridein, W. Grond,
A. Schönecker*

Surface Segregation, Microstructure
and Sinterability of α -Aluminum
Powders Doped with Magnesium
*M. Tebkoub, D. Monceau, M.C.
Amamira, C. Petot, G. Petot-Ervas*

Low Sintering PZT by Liquid Phase
Formation
H.-J. Gesemann, A. Schönecker

Electrical Conductivity of LaCrO_3
Sintered at Low Temperature
($<1400^\circ\text{C}$)
M.R. Morelli, R.J. Brook

Sinterability on Doped Lanthanum
Chromite
*K. Eichler, E. Syskakis, P.
Olschik, A. Naoumidies, K.
Jaenicke-Rößler*

Sinter Forging of Barium Titanate
I.J. Bennett, G. deWith

A New Method for Sintering of AlN
G. Hüttl, R. Dietrich

Chemical Preparation of Alkaline-
Earth Niobate Ceramics
K. Ehrhardt, M. Ittner, G. Werner

Preparation of Fine Well-Dispersed
Barium Titanate Powders by an
Emulsion Method
C.N. Elgy, P.R. Knott

Aqueous Phase Dispersion of
Barium Titanate Powders
*M.C. Blanco Lopez, L.A. Rahman,
F.L. Riley*

EVD of YSZ Films: Role of Gas
Phase Composition on Process
Efficiency
*T.F. Pais, F.M.B. Marques, G.P.
Wirtz*

Preparation Techniques and Charac-
terization of Very Thin ($<10\text{nm}$)
Aluminum Oxide Films
*D. Diesing, S. Rühle, M.M.
Lohrengel*

The Effect of Filmorine Anion on
Pore Size Distribution of Porous
Silica
S. Wang, H. Liu, L. Zhang, X. Yao

Novel Preparation Method and
Properties of PTS and PZTS Glass-
Ceramic
K. Yao, L. Zhang, X. Yao

Preparation and Properties of ZaS
Doped Glass
*H. Liu, S. Wang, S. Lu, L. Zhang,
X. Yao*

PLT Powders from Water Soluble
Precursors
H. Liu, L. Zhang, X. Yao

Sol-Gel Synthesis and Characteriza-
tion of a Conducting Ceramic/Metal
Composite
S. Dandoy, I. Baukens, M. Ghodsi

Processing and Physical Properties
of Sol-Gel Derived Nanostructured
 Ni-ZrO_2 Cermets
J. Großmann, K. Rose, D. Sporn

Zirconia-Tungsten Electrocomposite
*S. Vives, C. Guizard, L. Col, C.
Oberlin*

Properties of Ceramics-Copper Joint
"Directly Bonded" by Means of
Copper-Carbon Fiber Composite
*W.K. Wlosinski, Z. Librant, W.
Olesinska*

Electrotechnical Ceramics, Based on
Porcelain Stones of Kirgistan

S.J. Jelosheva, T.I. Koneshova

Gel Cordierite for Electronic
Packaging
A. Goldstein, V. Belov, I. Belov

Powder Preparation of Inorganic
Materials by Spray Drying
H.A.M. van Hal, W.A. Green

Electrophysical Properties of
 $\text{Ca}_5\text{Ga}_6\text{O}_{14}$ Single Crystals
S.L. Londar

Preparation of Materials With
Controllable Grain Boundary Size
From Water-Soluble Compounds
L.A. Reznichenko, O.N.

*Razunovskaya, L.A. Shilliona, V.A.
Aleshin, V.I. Makarov, Yu.F.
Korovin, V.G. Chiprinko, A.G.
Okhupkin*

Conformational Mechanism of
Pyroelectric Response in
Macromolecules Systems
N.N. Malveev, A.F. Klinskilch

A Possible Application of Volcanic
Stones for Electric and Electronic
Ceramics
E. Albert

Preparation of La Doped $\text{Sr}(\text{Ti}_{(1-y)}\text{Zr}_y)\text{O}_3$
($y=0\dots 1$) Dielectric Ceramic
Thin Films
S. Hoffmann, M. Klee, R. Waser

Hot-Forging of $\text{Ba}_{6-3x}\text{Sa}_{\text{d}+2x}\text{Ti}_{15}\text{O}_{54}$
Ceramics for Microwave
Applications
Ch. Hoffmann, R. Waser

Pulsed Laser Deposition and
Patterning of Electroceramic Thin
Films
*M. Mertin, D. Offenberg, C.W.
An, D.A. Wesner, E.W. Kreutz*

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CONFERENCE REPORTS**55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS****General Observations**

The 55th Autumn Meeting of the Japan Society of Applied Physics (Oyo Butsuri Gakkai) was held in Meijo University, Nagoya City, from **19 to 22 September 1994**. Nagoya City is in Aichi prefecture, and ideally located between the Kyoto-Osaka-Kobe and Tokyo metropolis, about 2 hours west from Tokyo and 1 hour east from Osaka by Shinkansen. Divided into 15 main sessions and 48 sub-sessions, the conference attracted more than 10,000 participants and there were about 3,500 presentations. Eighty-six presentations were made in the sub-session on thin films devoted to high permittivity materials and related topics, and 9 invited talks were given in a half-day symposium. The attendance varied between 150 and 200 researchers, almost only from Japanese companies and universities. This autumn, a presentation by Samsung, Korea, and the noted participation of Prof. S. Desu and Dr. J. Evans brought a slight international flavor to the meeting. Participation was once again roughly 50 percent from university and national research laboratory and 50 percent from industry. Contributed presentations at the Oyo Butsuri Gakkai last 15 minutes, including questions, and invited talks about 30 minutes. A booklet of abstracts is provided on the first day of the conference, but extended papers are not published afterwards.

This autumn, about 40 percent of the presentations were related to Pb-based titanates, 30 percent to SrTiO₃ and (Ba,Sr)TiO₃, and the remaining 30 percent to other materials (Bi₄Ti₃O₁₂, BaMgF₄, LiNbO₃, etc.). Though Pb-based materials are still the most studied materials, it should be noted that about 2/3 of the presentations on SrTiO₃/(Ba,Sr)TiO₃ were made by participants from industry. Each totaling about 25 percent of the presentations, the sputtering, sol-gel, and MOCVD techniques were the most reported preparation methods.

Main Features

The main features of this conference were:

- The disclosure of the composition of Y1 material by Olympus-Symetrix (20p-M-18, 20p-M-19, 20p-M-20) and Matsushita (20p-M-16). The "Y1 family" includes all materials which have the generic composition: (Bi₂O₂)²⁺(A_{n-1}B_nO_{3n+1})²⁻. They are bismuth oxide based layered superlattice materials, in which paraelectric (Bi₂O₂)²⁺ bismuth oxide layers are alternated with perovskitelike ferroelectric (A_{n-1}B_nO_{3n+1})²⁻ layers. Materials investigated by Olympus-Symetrix for possible nonvolatile memory application were SrBi₂Ta₂O₉, SrBi₂Nb₂O₉, SrBi₄Ti₄O₁₅ and solid solutions of these materials. According to T. Mihara from Olympus, the present choice for Y1 is SrBi₂Ta₂O₉, or SBTO. It shows a-axis polarization, with no 90° domains and no polarization along the c-axis, and a lower polarization is obtained than for PZT. NEC also reported on SBTO (20p-M-17), and presented SIMS data showing that Bi diffuses into Pt/Ti at the high annealing temperature of 800°C, required to obtain a large remnant polarization. Process improvements, such as lowering of the deposition temperature are necessary before practical integration of SBTO with conventional semiconductor devices.

- A presentation by Fujitsu on the preparation of an SrTiO₃/RuO₂/Ru structure on Si by MOCVD (19p-M-9). Ru(DPM)₂, Sr(DPM)₂-tetraen and Ti(i-OC₃H₇)₄ were used as the metal organic sources, O₂ as the oxidant and Ar as the carrier gas. It was reported that the introduction of some O₂ is necessary for Ru deposition. XRD data showed that the RuO₂(1000Å)/Ru(500Å)/Si structure thus prepared was stable after annealing for 30 minutes in air at 700°C. Ru and RuO₂ resistivities were 15 and 90 μΩ.cm, respectively. 1000 Å SrTiO₃ films prepared at 460°C exhibited a maximum dielectric constant of ε_r = 200, and XRD data showed that the SrTiO₃(1000Å)/RuO₂(1000Å)/Ru(500Å)/Si structure was unchanged by a 30 minutes annealing step in air at 600°C. However, when the deposition temperature was more than 500°C, SrTiO₃ films showed degraded electrical characteristics.

- A report by Mitsubishi on the TDS analysis of BST films prepared by liquid source MOCVD (19p-M-5). BST films were prepared by CVD on Pt/SiO₂/Si at T = 550~750 °C and P = 10 Torr, using Ba(DPM)₂ and Sr(DPM)₂

CONFERENCE REPORTS**55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS**

-- continued from page 16

dissolved in THF and $\text{Ti}(\text{i-OC}_3\text{H}_7)_4$ as liquid metalorganic sources. Samples were heated at a rate of $1^\circ\text{C}/\text{min}$ from 50 to 1000°C , and CO_2 ($m/e = 44$), CO ($m/e = 28$), H_2O ($m/e = 18$), CH_3 ($m/e = 15$), and C ($m/e = 12$) were monitored. H_2O , CO_2 and CO desorption occurred at 150°C , 400°C and 600°C , respectively. BST films with a composition of $(\text{Ba}+\text{Sr})/\text{Ti} = 1.1$ showed CO_2 desorption due to BaCO_3 in the films, whereas films with $(\text{Ba}+\text{Sr})/\text{Ti} = 0.9$ did not contain any BaCO_3 . The maximum CO peak was observed for $(\text{Ba}+\text{Sr})/\text{Ti} = 1.0$, and it was said that it corresponds to the presence of C in the perovskite structure. H_2O , CO_2 and CO peaks were also observed for sputtered BST films, and the explanation given for this phenomenon was that BST films absorb carbon and water from air.

•A report by Toshiba that $(\text{Ba}_x\text{Sr}_{1-x})\text{TiO}_3$ thin films epitaxially grown on Pt/MgO (100) show ferroelectricity for $0.44 \leq x < 1$ and paraelectricity for $0 \leq x < 0.44$ at room temperature (19a-M-11). BST films were prepared by co-sputtering of BaTiO_3 and SrTiO_3 targets at 600°C and 0.7 Pa in an Ar/O_2 mixture (40/10sccm). XRD peaks of the BST films showed epitaxial growth and a strong (001) peak for both $x = 0.24$ and $x = 0.68$. Due to the lattice mismatch of the BST films with the Pt substrate, the c -axis length measured for the films was larger than the one reported for bulk ceramics, and this could help explain the shift in the Curie temperature. A maximum dielectric constant of more than $\epsilon = 1100$ was measured at 100 kHz (0.1 V) and room temperature, for $\sim 2000\text{ \AA}$ BST films with $x = 0.24$.

•Reports by Kyoto University (20p-M-13) and Rohm (20p-M-14, 20p-M-15, 21p-M-8) on the use of Ir and IrO_2 as electrodes for PZT based nonvolatile memories and MFMS structures. Kyoto University reported the electrical characteristics of various MOCVD PZT based capacitors. For an $\text{Au}/\text{PZT}/\text{Pt}$ structure, $\epsilon_r = 479$, $P_r = 21.9\text{ }\mu\text{C}/\text{cm}^2$ and for an $\text{Ir}/\text{IrO}_2/\text{PZT}/\text{IrO}_2$, $\epsilon_r = 579$, $P_r = 9.0\text{ }\mu\text{C}/\text{cm}^2$. Moreover, leakage current increased from the $\text{Au}/\text{PZT}/\text{IrO}_2$ to the $\text{Ir}/\text{IrO}_2/\text{PZT}/\text{IrO}_2$ structure. Rohm previously reported on an MFMS structure with sol-gel PZT sandwiched between Ir/IrO_2 bottom and top electrodes ($\text{Ir}/\text{IrO}_2/\text{PZT}/\text{Ir}/\text{IrO}_2$). Ir and IrO_2 films were prepared by sputtering and annealed by RTA at $400\sim 700^\circ\text{C}$. It was shown this time that if PZT is deposited directly on IrO_2 , the electric characteristics are degraded (17 percent decrease in P_r after 10^{11} cycles). SIMS profiling showed that Pb diffuses in the bottom IrO_2 when PZT is grown directly on IrO_2 , but there is no Pb diffusion when PZT is grown on Ir/IrO_2 . Therefore, a metal barrier appears to be necessary between PZT films and the bottom IrO_2 electrode. No fatigue occurred for the $\text{Ir}/\text{IrO}_2/\text{PZT}/\text{Ir}/\text{IrO}_2$ structure with 200 nm PZT films, and C-V hysteresis could be observed.

•As mentioned above, there was a large number of presentations on SrTiO_3 and $(\text{Ba},\text{Sr})\text{TiO}_3$ by researchers from the semiconductor industry. Thanks to recent reports on the integration of SrTiO_3 and $(\text{Ba},\text{Sr})\text{TiO}_3$ with semiconductor memories, ST and BST are considered the most probable materials for use as capacitor dielectric in Gbit-scale DRAMs. Samsung, Texas Instruments Japan, Sharp, NEC, Fuji Electric, Toshiba, and Fujitsu reported on SrTiO_3 ; and NEC, Mitsubishi, Texas Instruments Japan, Toshiba, and Sharp reported on $(\text{Ba},\text{Sr})\text{TiO}_3$. Among Japanese large-volume DRAM makers, only Hitachi and Oki Electric did not report on ST or BST, and still focus their research on PZT.

•An increased number of reports on issues related to the integration of ferroelectric thin films with full capacitor processes. Sharp reported the high frequency characteristics of SrTiO_3 and $(\text{Ba},\text{Sr})\text{TiO}_3$ based capacitors with various configurations, for use in MMIC (19a-M-10). Capacitance remained constant up to 15 GHz for both ST and BST based small size capacitors ($1.5\sim 2\text{ pF}$). NEC reported on the step coverage of ECR CVD SrTiO_3 films (19a-M-2) and on the characterization of sidewall sputtered BST deposited on RuO_2 patterns (19a-M-10). Hitachi reported the electrical characteristics of PZT based capacitors, measured by contacting the Au top electrode and the backside of the wafers (20a-M-1). Poly-Si plugs were fabricated in an SiO_2 layer to connect the Pt/TiN bottom electrode and the Si

-- continued on page 18

CONFERENCE REPORTS

55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS

-- continued from page 17

substrate. A maximum charge storage of $280 \text{ fC}/\mu\text{m}^2$ was obtained at 1.5 V for 75 nm PZT films ($T_{\text{eq}} = 0.18 \text{ nm}$). Finally, there were two presentations on the etching of electrode materials. Mitsubishi reported the variation of the residue thickness on resist sidewalls for various Pt etching gas mixtures (22a-ZM-2). The best results were obtained for pure Argon (100 sccm at 5 mTorr). NEC showed the influence on RuO_2 etching of Cl_2 addition to an O_2 ECR plasma (22a-ZM-9). Using an SOG hard mask, fine RuO_2 patterns could be fabricated. A maximum etch rate more than $2000 \text{ \AA}/\text{min}$ and the best RuO_2 /SOG selectivity were obtained for 5 percent Cl_2 addition to the gas mixture.

Important tendencies reported for the previous Spring Oyo Butsuri Gakkai (*Ferroelectricity Newsletter*, Vol. 2, No. 3, Summer 1994) were again observed this autumn. Research results related to MFS, MFIS and MFMIS structures were widely reported, mostly by universities, such as Kyoto University (20p-M-13, 22a-M-6), The Tokyo Institute of Technology (22a-M-7, 22p-M-5, 22p-M-6, 22p-M-7), The Science University of Tokyo (22p-M-2, 22p-M-3, 22p-M-8), Osaka University (22p-M-4), and by Rohm on the company side (20p-M-14, 20p-M-15, 21p-MD-8). There were finally fewer reports on multilayers of ferroelectric materials than in the previous meeting, with reports on $\text{SrTiO}_3/\text{BaTiO}_3$ (21p-M-6), $\text{CaTiO}_3/\text{BaTiO}_3$ (21a-M-7) and $\text{PbTiO}_3/\text{PbZrO}_3$ (21a-M-9), all by Osaka University.

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PAPERS PRESENTED AT OYO BUTSURI GAKKAI -- AUTUMN 1994

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|----------|---|---|
| 19a-M-1 | Preparation of BaTiO_3 thin films by intense, pulsed, ion-beam evaporation | Nagaoka Univ.of Technology,
Nippon Seiki, Nichicon |
| 19a-M-2 | Improvement of electrical characteristics of RF sputtered SrTiO_3 films by multi-step deposition | Samsung Electronics |
| 19a-M-3 | Sputtering gas pressure effect on structure, morphology, and dielectric properties for $(\text{Ba},\text{Sr})\text{TiO}_3$ thin films | NEC |
| 19a-M-4 | Preparation of SrTiO_3 films by RF sputtering using He gas | Yamaguchi University |
| 19a-M-5 | Composition and dielectric constant in SrTiO_3 layers | Hosei University, Oki Electric |
| 19a-M-6 | Thickness dependence of the surface free energy for BaTiO_3 thin films | Nagaoka Univ. of Technology |
| 19a-M-7 | Dielectric properties of sputtered $(\text{Ba}_x\text{Sr}_{1-x})\text{TiO}_3$ thin films (III) | Mitsubishi Electric |
| 19a-M-8 | Influence of deposition temperature of Pt electrode on electrical properties of RF sputtered $(\text{Ba},\text{Sr})\text{TiO}_3$ thin films | Texas Instruments Japan |
| 19a-M-9 | Leakage mechanism of SrTiO_3 capacitor | Texas Instruments Japan |
| 19a-M-10 | RF characteristics of high dielectric thin film capacitors | Sharp |
| 19a-M-11 | Induced ferroelectricity in epitaxially grown $(\text{Ba},\text{Sr})\text{TiO}_3$ thin films | Toshiba |
| 19p-M-1 | Preparation of $(\text{Ba},\text{Sr})\text{TiO}_3$ thin films by sol-gel processing | Sharp |
| 19p-M-2 | Influence of reaction mechanisms on the step coverage of MOCVD SrTiO_3 thin films | NEC |
| 19p-M-3 | Electrical properties of SrTiO_3 prepared by electron cyclotron resonance plasma chemical vapor deposition | NEC |
| 19p-M-4 | Role of oxidizing agent in CVD of BST film | Mitsubishi Electric |
| 19p-M-5 | TDS analysis of BST thin films fabricated by CVD | Mitsubishi Electric |

-- continued on page 19

CONFERENCE REPORTS

55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS

-- continued from page 18

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| 19p-M-6 | Change in the physical properties of BaTiO ₃ thin films by controlling the preferred orientation of Pt electrode | Univ. Osaka Prefecture |
| 19p-M-7 | Axis orientation of SrTiO ₃ thin films of Pt (100) substrates | Fuji Electric |
| 19p-M-8 | Influence of lower electrode surface roughness on the electrical properties of SrTiO ₃ thin film capacitors | Toshiba |
| 19p-M-9 | Preparation of SrTiO ₃ /RuO ₂ /Ru/Si structure by the MOCVD method | Fujitsu |
| 19p-M-10 | Dielectric properties of sputter-deposited (Ba,Sr)TiO ₃ thin films on the sidewalls of fine-patterned electrodes | NEC |
| 19p-M-11 | Effect of buffer layer on the epitaxial growth of SrTiO ₃ thin films of Si (100) | Murata Mfg., Osaka Univ. |
| 19p-M-12 | Epitaxial growth of Ba _{1-x} Sr _x TiO ₃ films on Si substrates by pulsed laser deposition | Tokyo Inst. Technology |
| 19p-M-13 | Dielectric properties of epitaxial Ba _{1-x} Sr _x TiO ₃ films prepared by pulsed laser deposition on Si substrates | Tokyo Inst. Technology |
| 19p-M-14 | Effect of excimer laser annealing on SrTiO ₃ thin films (II)
Characterization by UV spectroscopy | Osaka Univ. |
| 19p-M-15 | Effect of excimer laser annealing on SrTiO ₃ thin films (III)
Application of excimer laser anneal to MIS structure | Osaka Univ. |
| 19p-M-16 | Effect of excimer laser annealing on SrTiO ₃ thin films
Analysis of laser anneal with internal stress | Osaka Univ. |
| 20a-M-1 | Properties of PZT thin films deposited by reactive evaporation | Hitachi |
| 20a-M-2 | Fabrication of PZT films on Si substrates using SrTiO ₃ buffer layers | Tokyo Institute of Technology |
| 20a-M-3 | Switching properties of PZT thin films prepared by dual-source vacuum evaporation | Tokyo Institute of Technology |
| 20a-M-4 | Preparation of Pb-based ferroelectric thin films using excimer laser | Matsushita Electric |
| 20a-M-5 | Preparation of PbTiO ₃ thin films by the laser ablation method (2) | Osaka University |
| 20a-M-6 | Microstructure of sputtered PbTiO ₃ thin films | RITE, Matsushita Electric |
| 20a-M-7 | Occurrence of defect surface layer in sputtered PZT films and its control | Oki Electric |
| 20a-M-8 | Preparation of PZT thin films by ECR sputtering (II) | Murata Manufacturing |
| 20a-M-9 | Electrical characteristics of low-temperature PZT thin films prepared by the digital MOCVD method | Tokyo Univ. Agri. & Tech.
Nissan Motor, Waseda Univ. |
| 20a-M-10 | Electrical evaluation of PZT thin films deposited by the laser MOCVD method | Himeji Inst. Techn., Osaka Gas,
KRI International |
| 20a-M-11 | Fabrication of PZT films by the laser MOCVD method (III) | Japan energy Corporation |
| 20p-M-1 | Large area growth of PLZT thin films by MOCVD | Kyoto University, Amaya Co. |
| 20p-M-2 | Step coverage of PbTiO ₃ thin films grown by surface reaction enhanced MOCVD | NEC |
| 20p-M-3 | Preparation of oriented PZT thin films by the sol-gel method | Sanyo |
| 20p-M-4 | Fabrication of ferroelectric PZT thin films by the sol-gel method | Sony |
| 20p-M-5 | Preparation of PZT thin films from chemically amplified photosensitive sol-gel solution (2) | Mitsubishi Materials |
| 20p-M-6 | Influence of buffer layers on the characteristics of sol-gel derived PZT thin films | Kanagawa University, Mitsubishi Materials |
| 20p-M-7 | Effect of Ti seeding treatment on the crystallization of sol-gel PZT | Texas Instruments Japan |
| 20p-M-8 | Examination of hysteretic leakage current through epitaxial ferroelectric thin films | Misubishi Kasei |
| 20p-M-9 | Effect of electrode materials on PZT film deposition by laser ablation (II) | Kanazawa Univ., Ishikawa Ind. Res. Inst. |

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CONFERENCE REPORTS

55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS

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| 20p-M-10 | Preparation of (Pb,Lu)TiO ₃ thin films by multiple cathode sputtering (III) | Shonan Inst. Tech., Waseda Univ. |
| 20p-M-11 | Interface reaction in MOCVD prepared PLZT/RuO ₂ /Si structure | Chubu University |
| 20p-M-12 | Preparation and properties of RuO ₂ and ITO as electrodes for ferroelectric thin films | Olympus Optical |
| 20p-M-13 | MOCVD growth and properties of PZT thin films on an IrO ₂ electrode | Kyoto University |
| 20p-M-14 | Study on PZT thin films prepared by the sol-gel method | Rohm, Mitsubishi Materials |
| 20p-M-15 | PZT thin films by the sol-gel method on IrO ₂ electrodes | Rohm |
| 20p-M-16 | Preparation and characterization of ferroelectric thin films by LSMCVD | Matsushita Electronics,
Symetrix, University of Colorado |
| 20p-M-17 | Fatigue characteristics of bismuth layer oxide thin films | NEC |
| 20p-M-18 | Development of Y1 (Bi layer structured ferroelectric) thin film capacitors (I) | Olympus Optical, Symetrix |
| 20p-M-19 | Development of Y1 (Bi layer structured ferroelectric) thin film capacitors (II) | Olympus Optical, Symetrix |
| 20p-M-20 | Development of Y1 (Bi layer structured ferroelectric) thin film capacitors (III) | Olympus Optical, Symetrix |
| 21a-M-1 | Cluster calculation of PbTiO ₃ tetragonal modification using ab initio molecular orbital method (1) | Nissan Motor, Waseda University |
| 21a-M-2 | Transient photocurrent of PZT ferroelectric thin films prepared by the MOCVD method | Kyoto University |
| 21a-M-3 | Two dimensional stress effect in ferroelectric thin film properties | The National Defense Academy |
| 21a-M-4 | Surface treatment and homoepitaxy of SrTiO ₃ (100) substrates by wet etching | Shinkosha Co., Tokyo Inst. Techn. |
| 21a-M-5 | Two-dimensional epitaxial growth of BaTiO ₃ thin films on SrTiO ₃ molecular step surface | Tokyo Inst. Techn., Shinkosha Co. |
| 21a-M-6 | Dielectric and IR properties of atomic order controlled SrTiO ₃ /BaTiO ₃ strained superlattices | Osaka University |
| 21a-M-7 | Crystal structure and dielectric constant of CaTiO ₃ /BaTiO ₃ superlattices | Osaka University |
| 21a-M-8 | Molecular dynamics simulation of the dielectric properties of (Sr,Ba)TiO ₃ (II) | Osaka University |
| 21a-M-9 | Preparation and characterization of PbTiO ₃ /PbZrO ₃ multi-layer films by the laser ablation technique | Osaka University, Kinki University |
| 21a-M-10 | SrTiO ₃ channel thin film transistor | Fujitsu |
| 21a-M-11 | Preparation of metal ferroelectric semiconductor FET using BaTiO ₃ thin films | Tokai University |
| 22a-M-1 | Preliminary study on the atomic layer epitaxy of ferroelectric thin films (II) | Tokyo Univ. Agri. & Tech.,
Nissan Motor, Waseda University |
| 22a-M-2 | CVD deposition process of PZT elements | Tokyo University of Agr. & Tech., Waseda University |
| 22a-M-3 | Interaction of CVD ferroelectric films with Si substrate (3) | Waseda Univ., Nissan Motor, Nissan ARC |
| 22a-M-4 | Effect of sputtering on the depth profile of ferroelectric films | Nissan ARC, Nissan Motor, Waseda Univ. |
| 22a-M-5 | Structure and SAW properties of LiNbO ₃ and LiTaO ₃ films grown by pulsed laser deposition | Asahi Chemical, Osaka University |
| 22a-M-6 | Preparation and electrical properties of LiNbO ₃ thin films prepared by RF magnetron sputtering | Kyoto University |
| 22a-M-7 | Preparation of LiNbO ₃ films on Si substrates by the sol-gel method | Tokyo Institute of Technology |
| 22a-M-8 | Study of a CeO ₂ epitaxial layer on Si as a buffer layer for MIS-FET | Asahi Chemical, Waseda University |
| 22a-M-9 | Synthesis and crystallographic characterization of YMnO ₃ thin films | Osaka Prefecture University |
| 22p-M-1 | Fabrication and characterization of ferroelectric Bi ₄ Ti ₃ O ₁₂ thin films by dipping pyrolysis of metal naphthenates | Science University of Tokyo |

-- continued on page 21

CONFERENCE REPORTS

55TH AUTUMN MEETING OF THE JAPAN SOCIETY OF APPLIED PHYSICS

-- continued from page 20

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| 22p-M-2 | Investigation of the effect of precursors on the crystallization of Bi ₄ Ti ₃ O ₁₂ thin films patterned by an electron beam | Science University of Tokyo,
SUT Yamaguchi College |
| 22p-M-3 | Investigation of the film quality dependence on the assist gas flow rate in the fabrication process of ferroelectric Bi ₄ Ti ₃ O ₁₂ thin films by MOCVD | Science University of Tokyo |
| 22p-M-4 | Preparation of Bi ₄ Ti ₃ O ₁₂ thin films by the laser ablation method | Osaka University |
| 22p-M-5 | Formation and evaluation of ferroelectric Pt/SiO ₂ /Si (100) structures | Tokyo Institute of Technology |
| 22p-M-6 | Growth temperature dependence of the interface characteristics of BaMgF ₄ /GaAs(100) | Tokyo Institute of Technology |
| 22p-M-7 | Electrical properties of ferroelectric BaMgF ₄ /Si structures (2) | Tokyo Institute of Technology |
| 22p-M-8 | Fabrication of crack-free BaMgF ₄ thin films on a limited area by vacuum evaporation | Science University of Tokyo |

ETCHING

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|----------|--|--|
| 22a-ZM-2 | Thickness of the sidewall deposited film in dry etching of platinum with various etching gases | Mitsubishi Electric, Ryoden Semiconductor System Engineering |
| 22a-ZM-9 | Effect on RuO ₂ etching of Cl ₂ addition to O ₂ plasma | NEC |

SYMPOSIUM

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|----------|---|------------------|-------------------|
| 21p-MD-2 | Electron theory of ferroelectricity | Pr. M. Tachiki | Tohoku Univ. |
| 21p-MD-3 | Polarization reversals in ferroelectrics | Pr. Y. Ishibashi | Nagoya Univ. |
| 21p-MD-4 | Fabrication methods and properties of ferroelectric thin films (1) CVD | Pr. T. Shiosaki | Kyoto Univ. |
| 21p-MD-5 | Laser ablation | Pr. T. Kawai | Osaka Univ. |
| 21p-MD-6 | Semiconductor memories with high dielectric constant ferroelectric material | Pr. Y. Tarui | Waseda Univ. |
| 21p-MD-7 | High permittivity materials for DRAM application | Dr. Y. Miyasaka | NEC |
| 21p-MD-8 | Applied ferroelectrics for nonvolatile memory | Dr. A. Kamisawa | Rohm |
| 21p-MD-9 | Application of ferroelectric thin films to neurodevices | Pr. H. Ishiwara | Tokyo Inst.Techn. |

PZT	(22)	SrTiO ₃	(16)	Bi ₄ Ti ₃ O ₁₂	(5)	Sputtering	(21)
PbTiO ₃	(8)	BaSrTiO ₃	(11)	SrBi ₂ Ta ₂ O ₉	(5)	Sol-Gel	(19)
PLZT	(3)	BaTiO ₃	(5)	LiNbO ₃	(4)	MOCVD	(18)
PLT	(2)	SrTiO ₃ /BaTiO ₃	(1)	BaMgF ₄	(4)	PLD	(14)
PbTiO ₃ /PbZrO ₃	(1)			LiTaO ₃	(1)	MBE	(7)
				CeO ₂	(1)	Evaporation	(5)
				YMnO ₃	(1)		

University - National Laboratory	(62)
Industry	(59)

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CONFERENCE REPORTS

6TH INTERNATIONAL SEMINAR ON FERROELASTIC PHYSICS

The 6th International Seminar on Ferroelastic Physics ISFP-6 was held in Voronezh, Russia, from 12 to 15 September 1994. The meeting was organized by the Department of Solid State Physics of the Voronezh State Technical University. It was the sixth in a series that began at Bologoe, Russia, in 1978 for the purpose of conveying a better understanding of ferroelastic properties in crystals undergoing structural phase transitions.

The seminar was arranged to link the subjects of an earlier chain of conferences on ferroelastics and recent studies of different crystals. Areas of current interest were covered by the following sessions: Phase transitions, lattice dynamics and soft modes, domain boundaries and other imperfections, spectroscopy, ferroelasticity and superconductivity, modulated phase, disordered systems, and applications. These sessions provided a forum for sharing the latest research results and technical developments, and a chance to meet old friends and make new ones.

Ten invited lectures and 57 posters were presented by about 70 participants. Recent achievements were reported during oral plenary presentations and poster sessions by leading experts in their respective areas. Also, there was a round table session on "Glasses and Glasslike States in Crystals," that raised lively interaction between participants and long, late night discussions.

Eight postgraduate researchers participated in ISFP-6 and presented contributed papers in various sessions.

Topics Presented

The seminar began with a general presentation by Prof. Lev A. Shuvalov, Institute of Crystallography, Russian Academy of Sciences (Moscow). During his welcome address, he described the **main events of ferroelastic physics and the latest research achievements in this area**. He made the important point that fundamental research should have strong ties to industry, which creates a long-term concern for technological and applied research development.

B.M. Darinsky (Voronezh, Russia) presented his work on the **acoustic axes of ferroelastic crystals**. He had theoretically solved a problem for a number of orientations of acoustic axes in the crystals of different crystallographic systems. In particular, it was shown that the quasi-longitudinal mode and quasi-shear modes of elastic oscillations are split practically for all crystals. In this way all possible systems of acoustic axes of ferroelastic crystals have been found. This approach made it possible to find a change of the acoustic axes systems caused by ferroelastic phase transition and a temperature variation.

Experimental aspects of the observation of modulated structure in the ferroelastic crystal KCOPO₄ were discussed in detail by H.Schmid (Geneva, Switzerland). He illustrated various methods, such as polarized light microscopy, X-ray precession photographs, and X-ray powder spectra, by showing their application to the study of the crystal structure and the features of ferroelastic domains with a "tweed" pattern typical of modulated structures. The modulation of the structure disappears when the crystals are ground to a grain size of less than 7 microns and are heated and cooled through the phase transition.

A.A. Bulbich (Rostov-on-Don, Russia) concentrated on the **theoretical analysis of nucleation in the low-symmetry phase near the elastic lattice defects**, such as dislocations, clusters, twin boundaries, cracks, and inclusions in improper ferroelastics. He described, for example, the nucleation that can take place not only near a defect at rest but also near a moving defect. In this case the order parameter distribution is compressed in the head of a moving defect and stretched in its back, i.e., the "trail" appears. It was shown that in the case of a first-order phase transition there is a place on the phase diagram in which the metastable trail exists.

The **characteristic features of the ferroelastic phase transitions between the low-conductive and superionic phases** were considered by A.I. Baranov (Moscow, Russia). Particular attention was focused on the improper ferroelastic phase transition in the superprotonic $\text{Me}_n\text{H}_5(\text{AO}_4)_p$ crystals. The review of the dielectric and ultrasonic experiments showed that the properties of disordered paraelastic as well as the ordered ferroelastic phases are of special interest to ferroelastic physics.

I.N. Flerov (Krasnoyarsk, Russia) gave a talk on the **experimental study of heat capacity near the phase transitions** and other properties depending both on hydrostatic pressure and atom replacements in ferroelastic crystals of several haloid perovskitelike families. He showed that the normalized shift of phase transition temperature under

CONFERENCE REPORTS

6TH INTERNATIONAL SEMINAR ON FERROELASTIC PHYSICS -- continued from page 22
 hydrostatic pressure has a characteristic value in different families for the same type of symmetry change. There exists a strong correlation between the number of layers linked to each other by common halogen atoms and thermodynamic characteristics of layered perovskites. It was shown that the behavior of physical properties near ferroelastic phase transitions can be described within the scope of thermodynamic theory.

V.Ya. Shur (Ekaterinburg) gave his talk on the **capabilities of elastic light scattering in ferroelastics and computer simulation for the study of domain evolution and phase kinetics**. He described the new approach to kinetics of phase transitions in ferroelastic crystals based on the model of geometrical transitions (catastrophes). It was demonstrated that the process of phase evolution in finite media can be described by expressions of the Kolmogorov-Avrami type. As a result, he developed the theoretical bases of a new technique, proposed the method of mathematical treatment of experimental results, and gave many examples about its possibilities, both topological and spectroscopic.

Included in **novel materials** discussed at the meeting was a **ferroelectric-superconductor ceramic composite** that is formed when ferroelectric-ferroelastic BaTiO₃ and superconductor YBa₂Cu₃O₇ are fired together at a high temperature. In some regions of concentration the materials are nonstoichiometric and undergo phase separation forming precipitates. This material may have various interesting applications.

The **eight poster sessions**, where all participants had the opportunity to present and discuss their current research activities, were highly successful. Lively discussions lasted long after the official ending of the sessions. This was largely due to the fact that all participants were lodged in the same hotel complex where the scientific activities took place.

The seminar also benefited from the **excellent facilities of the meeting site** and beautiful weather. Attendance at the lectures and at social events, including outdoor games, conference dinner, and after dinner talks, was high. The overall impression was that ISFP-6 has evolved into an interesting forum and that the policy of embracing new areas within the seminar topics should continue.

Part of the **proceedings of ISFP-6** will be published in a special issue of *Ferroelectrics* and also in Russian in *Izvestiya RAN, ser. fiz.* under the editorship of Lev Shuvalov, Moscow.

The ISFP series will continue in 1997 in Kazan, Russia, and will be organized by Kazan State University. I encourage scientists interested in ferroelastic physics and related topics to participate in the next conference and to contact the organizers.

-- Prof. S.A. Gridnev
 ISFP-6 Vice Chairman

<p style="text-align: center;">MEETINGS ANNOUNCED BY THE AMERICAN ASSOCIATION FOR CRYSTAL GROWTH</p> <p>Current Issues on Crystal Growth of Novel Electronics Symposium • 30 Apr-4 May • Cincinnati, OH Contact Dr. R.K. Pandey, Phone (409) 845-7449, Fax (409) 845-6259</p> <p>Fourteenth Conference on Crystal Growth and Epitaxy • 4-7 Jun • Fallen Leaf Lake, CA Contact Harold Olsen, Phone (310) 317-5927</p> <p>9th International Summer School on Crystal Growth • 11-16 Jun • Papendal, Arnhem, The Netherlands Contact +31 20 626 1372, Fax +31 20 625 9574</p> <p>The Eleventh International Conference on Crystal Growth • 18-23 Jun • The Hague, The Netherlands Contact +31 20 626 1372, Fax +31 20 625 9574</p> <p>Sixth Eastern Regional Conference on Crystal Growth • 15-18 Oct • Atlantic City, NJ Contact Stuart Samuelson, Phone (201) 361-2222</p>
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2ND PACIFIC RIM CONFERENCE ON FERROELECTRIC APPLICATIONS

The 2nd Pacific Rim Conference on Ferroelectric Applications took place in Melbourne, Australia, from 21 - 24 November 1994. In general, the conference was well organized, but the attendance was relatively small. Approximately 50 researchers from several countries were present. It is hoped that the conference will pick up momentum as it becomes more established in the ferroelectric community.

In the plenary session, good overview presentations were given on CVD (T. Shiosaki, Japan) and PEMOCVD (S. I. Woo, Korea) of ferroelectric thin films, mainly PZT family, on the status of ferroelectric integration and d.c. breakdown mechanisms in DRAMs (J. F. Scott, Australia), and an overview of device physics and modelling in ferroelectric storage cells (M. Huffman, USA).

Discussions on electrodes included good results on Ir/IrO₂ using PZT (T. Nakamura, Japan), and a very interesting discussion by L Sheldon (Australia) on biocompatibility considerations at electrode-neural interfaces. The possibilities of bioapplications of ferroelectric/piezoelectric materials should be thoroughly pursued.

On the theoretical side, papers on ferroelectric switching (Y. Ishibashi, Japan) and on the theory of frequency response of ferroelectric films (D. R. Tilley, Mapaysia) were presented. Various deposition techniques for ferroelectric films were discussed, such as excimer laser deposition, liquid source misted chemical deposition, and spin-on techniques. For device application, various presentations were given, including infrared sensors (S.T. Kim, Korea) and optoelectronic devices (D. Sengupta, Australia).

A session on biomedical applications and organic ferroelectrics informed us on PVDF applications (M. Podiasak, Australia, and H. L. W. Chan, Hongkong), and the talk on the status of cochlear and other implants by G. Clarke (Australia) provided valuable information. The last session of the conference was on characterization of ferroelectric materials and single crystal growth. Among the presentations in that session, the paper on HREM of relaxors gave an overview of the technique as well as the extensive modeling efforts in understanding domain structures (L. Bursili, Australia), and the one on heavy ion recoil spectrometry discussed the capabilities of the technique in bulk compositional analysis of thin film ferroelectrics (P. Johnston, Australia).

-- Maria Huffman, Symetrix Corporation, Colorado Springs, CO

FERROELECTRICS COMPUTERIZED INDEX

Compiled by **Sidney B. Lang**

Ben-Gurion University of the Negev, Israel

The *Ferroelectric Computerized Index* combines approximately 5500 entries including papers, editorials, book reviews, and errata from the three Gordon and Breach ferroelectrics journals: *Ferroelectrics* (1980 through 1992), *Ferroelectric Letters* (1982 through 1992), and *Integrated Ferroelectrics* (1992).

The index was compiled using Papyrus Retriever™ (Research Software Design, Portland, Oregon), which has fast powerful search capabilities allowing Boolean strategies and is compatible with most IBM software programs. Updates are planned.

This tool is now available **free** with any new paid 1995 journal subscription to *Ferroelectrics*. The index can also be purchased separately for \$60.

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CONFERENCE REPORTS

THIRD REGIONAL SEMINAR ON MICROELECTRONICS AND INFORMATION TECHNOLOGY

The third Regional Seminar on Microelectronics and Information Technology (TARSMIT '94) was held in Bangkok from 9 to 11 August 1994. Forty-one papers were presented. The conference may be of interest in that the participating countries (Thailand, Australia, Malaysia, Indonesia, Korea, Singapore, and the Philippines) are not often represented at North American or European conferences.

In addition to offering some insight into the level of microelectronics and information technology in these countries, the conference revealed emphasis on some practical problems of great financial impact, less related to ferroelectrics and high dielectrics, that are worthy of note. Highlights were microcomputer controller systems for small-industry applications, electricity use recording for individual consumers in apartment buildings, adaptive powerline interference cancellation in electrocardiography, and multiple microcomputer control of steam plants.

-- James Scott, Dean, Applied Science, RMIT Melbourne, Australia

Plenary Session - Overviews

CVD Deposition

T. Shiosaki

DC Breakdown Mechanisms in DRAMs

*J.F. Scott*PEMOCVD of PbTiO₃ and PZT*S.J. Woo*

Device Physics of Ferroelectric Storage Cells

*C.A Paz de Araujo***Electrodes and Interfaces; High Frequency Devices**

Ohmic Contact Characterization

*G. Reeves*Excellent PZT Memories with Ir/IrO₂ Electrodes*M. Takasu*

Is Titanium a Suitable Substrate for PZT?

P. Knight

Biocompatibility Considerations at the Electrode-Neural Interface

L. Seldon

Ferroelectric Phase-Shifters

D. Maddison

Theory of Frequency Response of Ferroelectric Films

*D.R. Tilley***Deposition Techniques**

Thin Films Deposited by Pulse Laser Ablation

Y.S. Kim

Preparation of PZT Films on SOI by Excimer Laser Deposition

L.C. Lu

Liquid Source CVD: Technology Status and Recent Results

*L.D. McMillan*Structure, Composition, and Pyroelectric Characteristics of PbTiO₃ Thin Films Deposited by ECR-PECVD*W.J. Lee*

Thin Film and Patterning Technologies for Integration of Ferroelectric Memories

K. Sakiyama

Production of Flexible Thin Film Oriented PZT Sensors by Sol-Gel

*G. Tulloch*Preparation and Properties of Nano-Crystalline Pb_{0.72}La_{0.28}TiO₃*W.G. Luo***MOD, RTP, Degradation**

Silicon Dielectric Engineering for the Nineties

H.B. Harrison

Influence of Rapid Thermal Annealing on Structural and Interfacial Properties of PZT Thin Films Prepared by Excimer Laser Deposition

L.C. Luo

An Expanded MOD System for Advanced Oxide Synthesis

M.C. Scott

MOD Technology for PLZT Nonvolatile RAMs and DRAMs

W. Zhu

Degradations in PZT Thin Film Capacitors

I.K. Yoo

Reliability of ASIC Devices

*R. Thornton***Device Applications**

Device Applications of Ferroelectric Thin Films

K.S. No

Memories, CCD Microprocessors, and Pyroelectric Detectors Based Upon Sol-Gel Ceramic Ferroelectric Films

A.S. Sigov

Electron Emission from PZT Thin Plate by Pulsed Electric Field

M. Okuyama

Fabrication and Characterization of a Thin-Film Infrared Sensor

S.T. Kim

Novel Deep Sub-Micron Device Structures

S. Dmitriev

Surface Laser Intensity Modulation Method (SLIMM)

S. Lang

Optoelectronic Devices

*D. Sengupta***Organics and Biomedical**

Application of PVDF Film Technology to Active Control of Water-Borne Noise

M. Podlesak

A Poling Study of PZT/P(VDF-TrFE) Copolymer 0-3 Composites

H.L.W. Chan

Hydropiezoelectrics -- Latest Developments

G.W. Taylor

C-V Properties of MIS Structures with a Ferroelectric Polymer Insulating Layer

I. Guy

Ferroelectricity in Inorganic-Organic Ionic Crystals

J. Liesegang

Cochlear and Other Implants

*G. Clarke***Growth and Characterization, Optical Effects**

The Crystallization Process and Electrical Properties of PZT Thin Films Deposited by Low-Temperature MOCVD

H. G. Kim

Growth of Lithium Tetraborate Single Crystals

R. Komatsu

High-Resolution Transmission Electron Microscopy of Relaxors

L. Bursill

Heavy-Ion Recoil Spectrometry of Barium Strontium Titanate Films

P. Johnston

Spontaneous Aperiodic Optical Switching in Crystalline Lead Magnesium Niobate

R. O'Sullivan

Numerical Modeling of Thermal Induced Optical Bistability in a Ferroelectric Fabry-Perot Cavity

X. Zheng

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UPCOMING MEETINGS

2nd International Conference on Space Charge in Dielectric Materials (CSC'2)**2 - 7 April 1995****Antibes, France**

This is the first meeting of the IEEE-DEIS Technical Committee on Space Charges in Dielectric Solids, organized by the French Vacuum Society in collaboration with the Association for the Advancement of Microtechnologies.

Topics

- Physics of space charges in dielectric solids
- Characterization of space charges
- Applications: dielectric breakdown fracture, wear, laser ablation
- Standards

Sessions

1. Synthesis of observations made during experiments related to dielectric breakdown, fracture, friction, and wear. These observations include, but are not limited to, the formation of space charges, structural changes, emission of particles, lifetime materials, probability of failure, etc.
2. Physics of space charges developed to explain the causes that led to previous observations and to guide the implementation of techniques for the characterization of space charges.
3. Characterization of space charges in order to evaluate different methods of characterization, to identify the elemental physical processes predicted by theory, to obtain data which can be directly compared and to reproduce data obtained by different techniques.
4. Applications aimed at demonstrating the impact of theoretical and experimental developments on technological processes and diagnostics.
5. Norms and expert systems: Definition of technical terms, measurables, procedures for testing and characterization, and statistics.

Sponsors

Ministry of Higher Education and Research; Ministry of Defense; Secretary of National Defense; Ministry of Foreign Affairs; Commission of European Community; Atomic Energy Commission; Alcatel Electronic Tubes; Leica.

Contact

SFV, 19, rue du Renard, 75004 Paris, France, Phone +33 142 78 15 82, Fax +33 142 78 63 20.

8th European Meeting of Ferroelectricity (8th EMF)**4 - 8 July 1995****University of Nijmegen, Nijmegen, The Netherlands****Topics**

- | | |
|--|---|
| <ul style="list-style-type: none"> Phase transitions and critical phenomena Electronic structure Lattice dynamics Charge-density wave systems Structure and growth Acoustic and ferroelastic properties Dielectric, piezo- and pyroelectric properties Optical properties. Phase conjugation Thin films, surfaces, small particles New materials | <ul style="list-style-type: none"> Modulated and incommensurate phases Disordered and glassy systems Domains, domain walls, imperfections Raman, Brillouin, IR spectroscopy X-ray, neutron, and electron spectroscopy Polymers (Anti)ferroelectric liquid crystals Ceramics and composite materials Sensors, actuators, transducers Ferroelectric/semiconductor integration |
|--|---|

Contact

Mrs. Rina Vos, Secretariat EMF8, Institute for Theoretical Physics, University of Nijmegen, Toernooiveld, 6525 ED Nijmegen, The Netherlands

UPCOMING MEETINGS

1st European Meeting on Integrated Ferroelectrics (EMIF1)**3 - 5 July 1995****University of Nijmegen, Nijmegen, The Netherlands**

EMIF1, a satellite conference of the 8th European Meeting on Ferroelectricity (EMF8), is a two and a half day, single session conference.

Topics

Thin film deposition	Electrodes and interfaces
Microstructure and characterization	Dielectric, ferroelectric, piezoelectric, and optical properties
Epitaxial structures	Domains and switching
Processing and integration	Memory devices
Thin film sensors and actuators	Thin film optical devices

Organizing Committee

P.K. Larsen, chairman; T. Rasing, secretary; R. Vos, secretariat

Contact

EMIF1, Theoretical Physics I, University of Nijmegen, PO Box 9010, NL-6500 GL Nijmegen, The Netherlands, Fax +31 80 652 120

Second International Workshop on Low-Energy Electrodynamics in Solids (LEES2)**26 - 30 June 1995****Trest', Czech Republic****Scope**

Workshop LEES2 is a continuation of the series started in 1993 as "International Workshop on Infrared and Millimeter Waves Spectroscopy" held at Bad Honnef, Germany. In order to make the topic slightly broader, we are including dielectric (impedance) spectroscopy in the lower frequency range and changed the title accordingly.

The aim of the workshop is to bring together experimentalists working in the field of dielectric spectroscopy in a broad sense (frequency range 0 - 10^{14} Hz) and theoreticians working in the field of low-energy excitations, both applied to various types of condensed matter systems. Emphasis will be laid on complex and disordered systems.

Topics

- Dynamics of freezing in disordered systems (classical, dipolar and quadrupolar glasses, polymers, relaxor ferroelectrics)
- Collective dynamics of quasicrystalline structures (charge and spin density waves, vortex dynamics in type II superconductors, domain wall dynamics, discommensurations in incommensurate systems, dynamics of nanoclusters)
- Low-energy excitations in superconductors
- Dynamical conductivity in fast ionic conductors
- Dynamics of structural and metal/nonmetal phase transitions
- Diffuse excitations in liquid crystals and liquid-crystalline polymers

Sponsors

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- Institute of Physics of the Czech Academy of Sciences
- ICARIS Ltd. Conference Management, Prague

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Dr. Jan Petzelt, LEES2 chairman, Institute of Physics, Academy of Sciences of the Czech Republic, Na Slovance 2, 180 40 Praha 8, Czech Republic. Phone +42-2-660-52166, Fax +42-2-82 1227, E-mail trest95@fzu.cz

CALENDAR OF EVENTS 1995	
Mar 20-22	<ul style="list-style-type: none"> 7th International Symposium on Integrated Ferroelectrics (ISIF 95), Colorado Springs, CO. For information contact Alona S. Miller, Symposium Coordinator, University of Colorado at Colorado Springs, PO Box 7150, Colorado Springs, CO 80933-7150. Phone (719) 593-3488, Fax (719) 594-4257
28-31	<ul style="list-style-type: none"> 42nd Spring Meeting of the Japan Society of Applied Physics, Tokai University in the Tokyo area, Japan. For information contact The Japan Society of Applied Physics, Kudanshita Bldg., 1-12-3 Kudan-kita, Chiyoda-ku, Tokyo 102, Phone +81 33 238 1044, Fax +81 33-221 6245
Apr 2-7	<ul style="list-style-type: none"> 2nd International Conference on Space Charge in Dielectric Materials (CSC'2), Antibes, France. For information contact SFV, 19, rue du Renard, 75004 Paris, France, Phone +33 142 78 15 82, Fax +33 142 78 63 20 (see p. 26)
May 24-27	<ul style="list-style-type: none"> 12th Meeting on Ferroelectric Materials and their Applications (FMA-12), Coop-Inn, Kyoto. For further information contact Dr. Tadashi Shiosaki, Electrical Engineering Department, Kyoto University, Yoshida-honmachi, Sakyou-ku, Kyoto-shi, Japan 606-01, Fax +81 75 753-5749
Jun 1	<ul style="list-style-type: none"> Deadline for First European Meeting on Integrated Ferroelectrics (EMIF1) manuscripts
26-30	<ul style="list-style-type: none"> Second International Workshop on Low-Energy Electrodynamics in Solids (LEES2), Trest', Czech Republic (see p. 27)
Jul 3-5	<ul style="list-style-type: none"> 1st European Meeting on Integrated Ferroelectrics (EMIF1), Nijmegen, The Netherlands (see p. 27)
4-8	<ul style="list-style-type: none"> 8th European Meeting on Ferroelectricity, University of Nijmegen, The Netherlands (see p. 26)
Aug 26-29	<ul style="list-style-type: none"> 56th Autumn Meeting of the Japan Society of Applied Physics, Kanazawa Institute of Technology, Kanazawa City, Japan. For information contact the Japan Society of Applied Physics, see address of Spring Meeting above
Aug 18-21	<p style="text-align: center;">1996</p> <ul style="list-style-type: none"> IEEE International Symposium on the Application of Ferroelectrics (ISAF '96), Brunswick Hilton and Tower, East Brunswick, NJ/Rutgers University. For information contact Prof. A. Safari, Rutgers University, Dept. of Ceramic Engineering & Center for Ceramic Research, PO Box 909, Piscataway, NJ 08855-0909, Phone (908) 445-4367, Fax (908) 445-3258, E-mail safari@safari.rutgers.edu